RENESAS

RAA215300

High Performance 9-Channel PMIC Supporting DDR Memory, with Built-In Charger and RTC

The [RAA215300](https://www.renesas.com/RAA215300) is a high-performance, low-cost 9-channel PMIC designed for 32-bit and 64-bit MCU and MPU applications. It supports DDR3, DDR3L, DDR4, and LPDDR4 memory power requirements. The internally compensated regulators, built-in Real-Time Clock (RTC), 32kHz crystal oscillator, and coin cell battery charger provide a highly integrated, small footprint power solution ideal for System-On-Module (SOM) applications. A spread spectrum feature provides an ease-of-use solution for noise-sensitive audio or RF applications.

The RAA215300 has six high-efficiency buck regulators and three LDOs to provide a complete power system. The internal device registers and EEPROM can configure and optimize the RAA215300 for different application requirements, for example, power sequences, output voltages, and switching frequencies. Dynamic Voltage Scaling (DVS) and Sleep modes are supported.

The RAA215300 is available in an 8x8mm, 0.5mm pitch thermally enhanced 56-lead QFN package and is specified for operation across a -40°C to 105°C ambient and -40°C to 125°C junction temperature range.

Features

- Input operating voltage range: 2.7V to 5.5V
- 6 synchronous buck regulators (supporting 5A, 3.5A, 2x1.5A, 1A, 0.6A), with settable V_{OUT}
- 3 LDOs (supporting 2x300mA, 50mA), with bypass mode, and settable V_{OUT}
- Dedicated VTTREF for DDR memory
- Auto PFM/PWM, FPWM and ultrasonic modes, with selectable PWM f_{SW}
- Built-in 32kHz crystal oscillator (with bypass), RTC, and coin cell/supercapacitor battery charger
- DVS and sleep modes
- Internally compensated
- Spread spectrum
- \cdot I²C serial interface (up to 1MHz)
- Pb-free (RoHS compliant)

Applications

- MCU/MPU/SoC consumer and industrial power
- FPGA system power
- Building/factory automation system power

Figure 1. Typical Application Diagram - MPU Power (RZ/G2L, RZ/G2LC, RZ/V2L)

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1. See [Multi Purpose I/O](#page-37-3) for pin function mapping.

2. All buck supplies (BUCKx_VINx) = AVDD = VCHG.

3. Specifications

3.1 Absolute Maximum Ratings

CAUTION: Do not operate at or near the maximum ratings listed for extended periods of time. Exposure to such conditions can adversely impact product reliability and result in failures not covered by warranty.

1. ≤20ns duration

3.2 Thermal Information

1. θ_{JA} is measured in free air with the component mounted on a high-effective thermal conductivity test board with direct attach features. See [TB379](https://www.renesas.com/www/doc/tech-brief/tb379.pdf).

2. For θ_{JC} , the case temperature location is the center of the exposed metal pad on the package underside.

3.3 Recommended Operation Conditions

Voltages referred to PGND unless otherwise stated.

3.4 Electrical Specifications

Components as described in [Recommended External Components.](#page-70-0) Additional application details in [Buck5](#page-60-5).

1. All the C_{OUT} listed in Test Condition are nominal values (not derated), unless stated as derated or effective. For details on the recommended components, see [External Component Selection](#page-69-0).

2. Parameters with MIN and/or MAX limits are 100% tested at +25°C, unless otherwise specified. Temperature limits established by characterization and are not production tested.

3. Follow this supply timing to ensure correct timekeeping of the RTC.

4. When a MPIOx is configured as full CMOS output, the sourcing current comes from VIO.

5. Compliance to datasheet limits is established by one or more methods: production test, characterization, and/or design.

6. At light loads, switching frequency is lower than the setting.

7. There is an internal 2MΩ pull-down resistor at each of the following pins: CEN, PWRON, MPIOx, and LDO_SELx.

4. Typical Performance Graphs

AVDD = VCHG = BUCKx VINx = 5V, BUCK1 FB = 1.1V, BUCK2 FB = 1.2V, BUCK3 FB = 1.8V, BUCK4 FB = 3.3V, BUCK5 FB = 1.2V, BUCK6_FB = 0.6V, CEN = HIGH, PWRON = HIGH, T_A = +25°C, unless otherwise stated. Refer to the [RTKA215300DE0000BU](https://www.renesas.com/RTKA215300DE0000BU) BOM for the components used in the following measurements.

Figure 4. Buck1 Efficiency in Auto PFM/PWM mode Figure 5. Buck2 Efficiency in Auto PFM/PWM mode

Figure 6. Buck3 Efficiency in Auto PFM/PWM mode Figure 7. Buck4 Efficiency in Auto PFM/PWM mode

Figure 8. Buck5 Efficiency in Auto PFM/PWM mode Figure 9. Buck6 Efficiency in VTT configuration (FPWM mode)

5. Serial Interface

The RAA215300 includes a standard I²C serial interface. The 2-wire interface links one or more Masters and uniquely addressable Slave devices. The Master generates clock signals and is responsible for initiating data transfers. The serial clock is on the SCL line and the serial data (bidirectional) is on the SDA line. The RAA215300 supports clock rates up to 1MHz (Fast mode plus) and is downward compatible with standard 100kHz (Standard mode), and 400kHz (Fast mode) clock rates.

The SDA and SCL lines must be HIGH when the bus is free (not in use). An external pull-up resistor (typically 1kΩ to 4.7kΩ depending on clock speed, pull-up voltage, and bus capacitance) or current source is required for SDA and SCL.

The I²C interface is not functional until VIO_PGOOD is high. See [VCHG, VBAT, and VRTC](#page-33-3) for more details.

5.1 I2C General Operation

5.1.1 Data Validity

The data on the SDA line must be stable (clearly defined as HIGH or LOW) during the HIGH period of the clock signal. The state of the SDA line can only change when the SCL line is low (except to create a START or STOP condition). The voltage levels used to indicate a logical 0 (LOW) and logical 1 (HIGH) are determined by the V_{II} and V_{IH} thresholds, respectively, see [Electrical Specifications](#page-10-1).

5.1.2 START and STOP Condition

All I²C communication begins with a START condition (indicating the beginning of a transaction) and ends with a STOP condition (signaling the end of the transaction).

A START condition is signified by a HIGH-to-LOW transition on the serial data line (SDA) while the serial clock line (SCL) is HIGH. A STOP condition is signified by a LOW-to-HIGH transition on the SDA line while SCL is HIGH. See timing specifications in ²C Timing.

The Master always initiates START and STOP conditions. After a START condition, the bus is considered busy. After a STOP condition, the bus is considered free. The device supports repeated STARTs, where the bus remains busy for the continued transaction(s).

5.1.3 Byte Format

Every byte on SDA must be 8 bits in length. After every byte of data sent by the transmitter, there must be an Acknowledge bit (from the receiver) to signify that the previous 8 bits were transferred successfully. Data is always transferred on SDA with the most significant bit (MSB) first. If the data is larger than 8 bits, it can be separated into multiple 8-bit bytes.

5.1.4 Acknowledge (ACK)

Each 8-bit data transfer is followed by an Acknowledge (ACK) bit from the receiver. The ACK bit signifies that the previous 8 bits of data were transferred successfully (master-slave or slave-master).

When the Master sends data to the Slave (for example, during a WRITE transaction), after the 8th bit of a data byte is transmitted, the Master tri-states the SDA line during the 9th clock. The Slave device acknowledges that it received all 8 bits by pulling down the SDA line, generating an ACK bit.

When the Master receives data from the Slave (for example, during a data READ transaction), after the 8th bit is transmitted, the Slave tri-states the SDA line during the 9th clock. The Master acknowledges that it received all 8 bits by pulling down the SDA line, generating an ACK bit.

5.1.5 Not Acknowledge (NACK)

A Not Acknowledge (NACK) bit is generated when the receiver does not pull down the SDA line during the acknowledge clock (that is, the SDA line remains HIGH during the 9th clock), indicating to the Master that it can generate a STOP condition to end the transaction and free the bus.

A NACK bit can be generated for various reasons, for example:

- \bullet After an I²C device address is transmitted, there is NO receiver with that address on the bus to respond.
- The receiver is busy performing an internal operation (for example, reset or recall) and cannot respond.
- The Master (acting as a receiver) must indicate the end of a transfer with the Slave (acting as a transmitter).

5.1.6 Device Address and R/W Bit

After a valid START condition, the first byte sent in a transaction contains the 7-bit Device (Slave) Address plus a direction (R/W) bit (Device Address Byte). The Device Address identifies which device (of up to 127 addresses on the I^2C bus) the Master wishes to communicate with.

After a START condition, the device monitors the first 8 bits received (Device Address byte), and checks for its 7-bit Device Address in the MSBs. If it recognizes the correct Device Address, it ACKs and becomes ready for further communication. If it does not see its Device Address, it sits idle until another START condition is issued on the bus.

Note: The 8th bit (LSB) of the Device Address byte indicates the direction of transfer, READ or WRITE (R/W). A 0 indicates a WRITE operation - the Master transmits data to the RAA215300 (receiver). A 1 indicates a Read operation - the Master receives data from the RAA215300 (transmitter).

5.2 Device Communication Protocol

5.2.1 7-bit Device Addresses

The RAA215300 employs two 7-bit I²C device/slave addresses. One address accesses settings related to the RTC function (RTC Slave Address) - default address **0x6F** (1101111x). Another address accesses the remainder of the device settings (Main Slave Address) - default address **0x12** (0010010x). The LSB is a direction bit, which can be 0 for a WRITE or 1 for a READ, which is not part of the unique 7-bit I²C device address.

Both addresses are programmable in EEPROM with possible values in the range 0x01 to 0x7F. The two slave addresses can be the same value for single slave address access to the register space.

5.2.2 Register Size

All the device registers contain 8-bit (byte) data. The data is latched-in after the 8th bit (LSB) is received. If a partial data byte is received, that byte is ignored, but any previously acknowledged bytes are accepted.

5.2.3 I2C Write Operation

A Write operation consists of the master sending a START condition, followed by a valid device address byte (R/W bit set to 0), a Register Address Byte, Data Byte, and a STOP condition. After each byte, the device responds with an ACK. The $12C$ protocol supports burst writing (automatic incrementing of address pointer). After every successfully transmitted data byte, the device automatically increments the internal register address, so subsequent data bytes are written to sequentially incremental register locations. The master must send a STOP condition after sending at least one full data byte and receiving the associated ACK. If a STOP is issued in the middle of a data byte, the Write for that byte is not performed. The basic write transaction structure is shown in [Figure 10.](#page-29-1)

	- 		u		-				\sim		-	e	௳	Host
œ - S	Device 1^2C . ن Address		v	\checkmark \circ		Reg Address M		\checkmark ÷ ◡		Write Data to Reg M		$\overline{}$ ◡	\circ ഗ	Slave

Figure 10. 1-Byte Write to Register M

5.2.4 I2C Read Operation

The master sends a START condition, followed by a valid device address byte (R/W bit set to 0), a register address byte, a second (repeated) START, and a valid device address byte (R/W bit set to 1). After each of the three bytes, the device responds with an ACK. The device then transmits data bytes back to the master, and the master ACKs after each byte. The master terminates the Read operation by issuing a NACK and sending a STOP condition.

After every successfully transmitted data byte, the device automatically increments the internal register address, so data bytes are sent out from sequential register locations.

Figure 12. 1-Byte Read to Register M

Figure 13. L-Byte Sequential Data Read Starting at Register M

5.2.5 I2C Timing

The timing specifications of the I²C I/O from the I²C specification are shown in [Figure 14](#page-30-1) and [Table 1](#page-30-2). The I²C controller provides a slave I²C transceiver capable of interpreting I²C protocol in Standard, Fast, and Fast-mode plus modes.

Figure 14. I2C Timing Definitions

Table 1. I2C Timing Characteristics

1. t_{HD:DAT} is the data hold time that is measured from the falling edge of SCL, applies to data in transmission and the acknowledge.

2. V_{DD} = External pull-up voltage.

3. In Fast mode Plus, fall time is specified the same for both output stage and bus timing. If series resistors are used, designers should allow for this when considering bus timing.

5.3 Unimplemented Registers

All register addresses that are defined in the register map ACK write commands and return data to read commands that address them. Unimplemented registers address ACK write commands but data is ignored, and returns a fixed value of 0x00 to read commands.

6. Registers and EEPROM

The RAA215300 features both volatile (RAM/registers) and non-volatile (EEPROM) memory. The volatile value of each register can be set by writing data to the appropriate register using the selected interface, or it can be recalled and loaded from the integrated EEPROM.

When the device enters into {READ_EE}, digital logic loads the pre-programmed EEPROM data into the volatile register space. When all data is loaded successfully, the device does not reload EEPROM data again unless there has been a power cycle, CEN toggle, or software reset command. See Operating {States} and Transition [Conditions.](#page-34-0)

Volatile register data can be written or read back on the fly, as fast as the I2C interface can support.

6.1 EEPROM

The RAA215300 integrates high endurance EEPROM to store all IC configurations. The EEPROM is capable of 1000 plus endurance cycles and 10yrs at 85C of data retention.

6.1.1 Writing to the EEPROM

EEPROM programming is initiated through a control byte register. When setting the write bit to 1 in the control byte (0xFF), all the related non-volatile register data are copied to EEPROM on the subsequent I²C STOP condition. During the EEPROM programming cycle time, the device is internally busy and NACKs to any interface commands, however the buck, LDO outputs, and other IC operations are not halted during the programming time.

When the programming cycle completes, the stored EEPROM data is automatically read back into the register. This provides a way for the host to validate successful programming by reading back the register(s) and comparing it with the value(s) intended to be programmed. If values match, programming was successful. However, if the register data reverts to the previous stored EEPROM value, the EEPROM values were not successfully updated.

6.1.1.1 EEPROM Banks

The RAA215300 EEPROM is partitioned into eight separate banks. All customer banks are (re)programmed each time an EEPROM programming operation commences. For details about each register and bits, see the [Register](#page-77-0) [Map.](#page-77-0)

6.1.1.2 EEPROM Programming Voltage

When programming the EEPROM, the minimum voltage requirement must be met:

▪ VPROG ≥ 21V

If the condition is not met, the EEPROM programming operations are not successful. If there was insufficient EEPROM programming or reading voltage, the NVM_Error_Latched and EE_Error_Latched bits are set to 1. The fault flags do not affect the power-on sequencer.

6.1.1.3 Step-by-Step EEPROM Programming Instructions

- 1. The device should be in {STANDBY} or onward.
- 2. Write/set up all the required register values (volatile).
- 3. Apply sufficient EEPROM programming cycle voltage to VPROG, see [EEPROM Programming Voltage](#page-31-4).

Note: This step can occur before Step 2.

- 4. Set the write bit in the control byte write register address 0xFF[1] = 1. On the subsequent I²C stop condition, the EEPROM programming cycle commences.
- 5. The system must wait for the maximum t_{EE} wRITE time to elapse before attempting further interface activity with RAA215300, or making any changes to the supplies as the device is internally busy with programming operations.

6.1.2 Recalling the EEPROM

There are two ways to load EEPROM data to the device volatile registers:

- Automatic Recall Occurs during initial power-on (or power cycle). See Operating {States} and Transition [Conditions.](#page-34-0)
- Manual/Software Recall Issue an I²C reset command to the control byte (register 0xFF).

When the EEPROM is being loaded to the registers, the device is internally busy and NACKs to any I²C commands. When all data is loaded successfully, the RAA215300 does not reload the data unless there has been a new power cycle, toggle of CEN, or software recall command.

6.1.2.1 Valid EEPROM Data Check

During the initial automatic recall, the device provides a safety mechanism to effectively stall the power-on process (sequencer) before any blocks become enabled, and output sequencing starts if it is determined that the EEPROM data has not been programmed or checked by the host. This is accomplished by putting the device into ${F A ULT}$ OUT}, which allows the system host to first read back by I²C and initially program the EEPROM data loaded to the registers or confirm loaded data are valid for the application. This helps prevent any undesirable application system behavior. The host can verify this event occurred by reading the fault registers and observing if the NVM_Error_Latched fault and Valid_EE_Data latched fault bits are set to 1. This feature is not enabled if registers 0xD9 - 0xDD are all at zero value.

If the register and/or EEPROM data must be changed after the host checks any required register data, the host can make the necessary programming changes. When correct register data is set, the host should clear the NVM_Error_Latched fault by writing 1 to it, which clears both NVM_Error_Latched and Valid_EE_Data bits and releases the device to continue the power-on as determined by PWRON and configuration register settings. This gives the host authority to validate the register settings and specifically control when the device is allowed to start the system.

When the required RAA215300 settings are fixed and programmed to EEPROM (that is, the host no longer requires to validate the data at each power-on), programming register EEPROM_ID_1 or EEPROM_ID_2 to any non-zero value in EEPROM authorizes that the EEPROM data is valid. Therefore, the device no longer enters {FAULT_OUT} and awaits host intervention at subsequent power-on events. *Note:* Reprogramming register EEPROM_ID_1 and EEPROM_ID_2 back to 0x00 value causes the device to enter {FAULT_OUT} at future power-on events.

6.2 EEPROM Error Correction

Data stored in EEPROM is protected by error correction codes (ECC), which allows a single bit error in a given memory bank to be corrected. Each EEPROM bank is covered by its own error correction code.

When a bank of EEPROM is programmed, the error correction code for that bank is automatically generated internally and stored in the same bank. When the EEPROM is recalled, the error correction code is checked, and a correctable (single bit) error is automatically corrected.

Should a single bit correction occur, the EE_Bank#_ECC_Corrected status flag and NVM_Error_Latched bit are set. INT# is asserted. The device still transitions states normally to start up. The host can clear the NVM_Error_Latched fault by writing 1 to it, which clears both NVM_Error_Latched and EE_Bank#_ECC_Corrected bits and de-asserts the INT# output. Two-bit errors in any bank are detected and reported as uncorrectable errors by setting the INT# interrupt event, NVM_Error_Latched bit, and EE_Bank#_ECC_Error status flags. The device ignores the other control inputs (such as PWRON) and enters

{FAULT_OUT}. The host should clear the NVM_Error_Latched fault by writing 1 to it, which clears both NVM_Error_Latched and EE_Bank#_ECC_Error bits and releases the device to continue the power-on sequence.

6.2.1 ECC Bank Detail Bits

Each RAA215300 memory bank has dedicated ECC bank detail fault bits to uniquely report if a given bank had either an uncorrected, or corrected ECC error occur. These bits do not affect IC operation, they are simply used to provide additional information in the event of ECC operation.

When an ECC error is uncorrected for a given bank # (that is, EEPROM EE_Read_Error interrupt event occurs), a corresponding detail status bit (EE_Bank#_ECC_Error) is set to 1. The EE_Bank#_ECC_Error status bits can be cleared by writing 1 to the NVM_Error_Latched bit.

When an ECC error is corrected for a given bank #, a corresponding detail status bit (EE_Bank#_ECC_Corrected) is set to 1. The bit(s) can be cleared by the host by writing 1 to the NVM Error Latched bit.

7. Power Supplies

The RAA215300 requires one input power supply to power everything. To describe various usage of the power supply, it is helpful to give it various names, but all named parts must be connected together by the PCB. AVDD and VCHG are defined in [Pin Descriptions](#page-6-2). The input power supply provides power to all voltage regulators, and these connections have various names defined in [Pin Descriptions](#page-6-2). Connection to the IC is made at many physical locations, identified by name, and each location must have dedicated decoupling capacitance.

7.1 Internal LDO (VIO)

An LDO rejects noise from the VCHG supply and provides a quiet and stable internal supply, VIO, for interface logic.

The LDO is output-compensated and requires a minimum of 1.2µF effective output capacitance, placed close to the VIO pin. See [External Component Selection](#page-69-0) and [Device Specific Layout Guidelines.](#page-74-2)

VIO is enabled as soon as AVDD exceeds its UVLO rising threshold. VIO power-good (VIO_PGOOD) is monitored only after EEPROM is read. The timeout period starts as soon as the FSM enters {WAIT_FOR_VIO}. The timeout period is set by a 2-bit register. See [{WAIT_FOR_VIO}](#page-34-3).

A register bit is assigned to mask or unmask the VIO PGOOD signal from INT#. Another register bit shows the status of the VIO power-good fault. When asserted, this fault flag is latched and does not clear automatically. It can only be cleared by writing 1 to the register, hardware reset, or input power cycle.

The VIO LDO is capable of supporting an additional external load of up to 20mA continuously.

7.2 VCHG, VBAT, and VRTC

VRTC is an output that provides power to the RTC. VRTC is generated internally from the higher of VBAT and VCHG. If RTC is used, Renesas recommends placing a capacitor footprint between VRTC and AGND. The capacitor is not populated by default. If RTC is not used, leave VRTC open.

VCHG is the power supply for the coin cell charger and the internal LDO VIO. VCHG must be connected to AVDD, allowing I^2C to be operational when the RTC is in battery mode while AVDD remains above its UVLO falling threshold (for example, AVDD = 2.7V, VBAT = 3V). Given that the input thresholds of the I²C signals depend on the VIO supply, which is derived from VCHG, the I/Os are effectively disabled when VIO_PGOOD is LOW (invalid). This could occur when CEN is LOW (the main IC is shut down) if AVDD is below its UVLO level, or when the VIO LDO is powering up.

VBAT can be connected to a coin cell battery or a supercapacitor. VBAT is selected to supply VRTC when VCHG falls below the VBAT voltage - entering battery mode operation. When VCHG rises above (VBAT + VBAT_{HYS}), the system selects VCHG to supply VRTC.

8. Operating {States} and Transition Conditions

The RAA215300 has a finite-state machine (FSM) to execute transitions between various operational states. The following describes those states and the conditions for transitions.

8.1 {RESET}

If AVDD is below its UVLO falling threshold in any state or CEN = LOW in {STANDBY} or {FAULT_OUT}, the device enters {RESET}. In {RESET}, the digital circuit is held in reset, and if CEN = LOW, the device is powered down. When AVDD is above its UVLO rising threshold and CEN = LOW, the device is in the SHUTDOWN condition.

8.2 {READ_EE}

When AVDD is above its UVLO rising threshold and CEN = HIGH, EEPROM values are read into the registers. When EEPROM reading/loading is successfully completed, the device sets the NVM_Read_Complete latched flag and then transitions to {WAIT_FOR_VIO}.

Note: There is an error correction system (1-bit error correction and 2-bit error detection) that checks the EEPROM loads correct data. If EE_Bankx_ECC_Error or Valid_EE_Data errors are detected, the state machine sets the NVM_Error_Latched flag bit. If this occurs, the part ignores control inputs (for example, PWRON) and enters {FAULT_OUT}. See [Valid EEPROM Data Check](#page-32-2) and [EEPROM Error Correction.](#page-32-1)

8.3 {WAIT_FOR_VIO}

{WAIT_FOR_VIO} follows successful {READ_EE}. Providing that AVDD is valid and that CEN is high, on entry to {WAIT_FOR_VIO}, a programmable timer (VIO Timeout) starts, and monitoring of VIO_PGOOD begins. If VIO_PGOOD is asserted before the timer expires, the FSM transitions to {STANDBY} before the end of the timeout period. If VIO PGOOD is not asserted when the timer expires, the FSM transitions to {FAULT_OUT}.

8.4 {STANDBY}

In {STANDBY}, MPIOx (if configured as inputs) and PWRON are responded to. The I²C interface becomes operational as well. When PWRON is asserted, the FSM enters {STANDBY_EXIT}.

8.4.1 {STANDBY_EXIT}

The FSM stays in this state until a timer expires (typically around 80µs). When the timer expires, the FSM enters {STANDBY_TO_ACTIVE}.

8.4.2 {STANDBY_TO_ACTIVE}

In {STANDBY_TO_ACTIVE}, the output rails are turned on if enabled in the register settings, and MPIOx is asserted if configured as outputs in the register settings. MPIOx can also be configured to inputs that control regulator output power-on timing. See [Power-ON](#page-45-1) for details.

8.4.3 {ACTIVE_TO_STANDBY}

In {ACTIVE}, if PWRON is de-asserted, the FSM transitions to {ACTIVE_TO_STANDBY}. The FSM enters {STANDBY} when the outputs complete the programmed power-off sequence.

8.5 {ACTIVE}

When the output rails and MPIOx complete the programmed power-on sequence, the FSM enters {ACTIVE}.

8.6 {IORESET}

There are three possible causes of the device entering {IORESET}:

- CRST_IN# is asserted when CRST_Fault_EN = LOW
- The watchdog timer expires when WD_PD_EN = LOW
- WD_RST_EN = HIGH; or Warm Reset = HIGH

The MPIOx reset outputs are asserted immediately. See [Warm and Cold Reset](#page-48-0) for details. While in this state, if PWRON is de-asserted, the device transitions to {ACTIVE_TO_STANDBY}.

8.6.1 {IORESET_TO_ACTIVE}

When reset is complete, the reset register bit is cleared automatically and the device enters {IORESET_TO_ACTIVE}. While in {IORESET_TO_ACTIVE}, if PWRON is de-asserted, the FSM enters {ACTIVE_TO_STANDBY}.

8.7 {SLEEP}

{SLEEP} is a mode of operation with selectable alternative power rails settings. Different output voltages may be set, and the buck regulators can each be set to a different operating mode.

While in {ACTIVE}, if SLEEP# is asserted or the SLEEP_State_EN bit is HIGH, the FSM enters {ACTIVE_TO_SLEEP}.

8.7.1 {ACTIVE_TO_SLEEP}

There are two output voltage settings for each rail - one for {ACTIVE} and one for {SLEEP}. When entering {SLEEP}, the voltage transitions to {SLEEP} settings following the power-off sequence. If the voltage settings are different for the two states, the voltages ramp up or ramp down according to the programmed DVS slew rate. When slewing of all output voltages completes, the FSM enters {SLEEP}.

8.7.2 {SLEEP_TO_ACTIVE}

While in {SLEEP}, if SLEEP# is de-asserted or the SLEEP_State_EN bit is LOW, the FSM transitions to {SLEEP_TO_ACTIVE} following the power-on sequence. If the voltage settings are different for the two states, the voltages ramp up or ramp down according to the programmed DVS slew rate. When all output voltage changes complete, the FSM enters {ACTIVE}.

8.8 {FAULT_OUT}

If a fault condition occurs, the FSM enters {FAULT_OUT} after completing the power-off sequence (see Device [Monitors, Warnings, and Protections](#page-64-2)). Depending on the fault type and configured response, the device may turn off all outputs in {FAULT_OUT}. INT# is pulled LOW if not masked from that particular fault. If CEN = LOW, the device enters {RESET}. To exit {FAULT_OUT} and enter {STANDBY}, the fault condition(s) must cease, and all latched fault bits must be cleared by writing 1 to the fault register bit(s).

If the latched fault bit is cleared before all the outputs have finished turning off, the power-up sequence can begin with some outputs already enabled. This behavior can be avoided if necessary by ensuring that there is sufficient delay before clearing the latched fault bit. Alternatively, the cold reset function [\(Warm and Cold Reset\)](#page-48-0) can be triggered immediately before clearing the latched fault bit to ensure that the power-down sequence completes before powering up again.

FSM_PWRON = CEN & PWRON & !FSM_FAULT & !I2 C_TRIGGER_RESET & !COLD_RESET

FSM_RESET

- CRST_IN# is asserted when CSRST_FAULT_EN = LOW
-
- WDT Expires when WD_RST_EN = HIGH and WD_PD_EN = LOW
- Warm Reset = HIGH

FSM_SLEEP = SLEEP State EN | SLEEP#

Figure 15. State Diagram

9. Functional Blocks and Application Information

9.1 Chip Enable

The device chip enable (CEN) is an active high, level-sensitive input. When asserted (HIGH), it provides a whole chip enable signal, and when de-asserted (LOW), it disables the device, and all outputs are tri-stated. CEN supports being tied to AVDD. See [Electrical Specifications](#page-10-0) for pin capability.

When asserted, the internal bias circuits power up and check to see if AVDD is above the UVLO threshold. CEN going low in any state where outputs are active causes a sequenced power-down and a transition to {STANDBY}, then onward to {RESET}. If CEN goes low in {ACTIVE} and goes high before the power-off sequence completes, the outputs restart following the power-on sequence when CEN = HIGH and PWRON is asserted without entering {RESET}.

When the power-off sequence is triggered by CEN going low, a shutdown period starts when the last output is powered off. The maximum Tshutdown setting of the output rails sets the shutdown period. At the end of the shutdown period, the FSM transitions to {STANDBY} and then {RESET}, which means the on-chip active discharge circuit stops working, and the output capacitors discharge by the external load current.

Note: When a fault or PWRON de-assertion triggers the power-off sequence, CEN being low is ignored if CEN goes low during the sequencing and goes back high before the sequence completes.

9.2 PWRON

Power-on (PWRON) is a configurable input offering with an on/off switch or push button support. PWRON polarity is configurable in both on/off switch and push-button mode. When configured as an on/off switch, the input is an active high or low (depending on the polarity setting) level-sensitive input. When configured as a push-button input, the input must be asserted low or high (depending on the polarity setting) for a programmable long duration (in seconds) to internally set the PWRON signal. The supported periods are 1s, 1.5s, 2s, and 3s. A long push button is required for initiating each of the power-on and power-off sequences.

When the internal PWRON signal is asserted, the FSM enters {STANDBY_EXIT}, then onwards to {STANDBY_TO_ACITVE} where it enables the regulators and starts the power-on sequence following the configurations loaded from EEPROM. When the internal signal is de-asserted, all the regulators are powered down, and the MPIOx outputs are asserted following the sequence configured in the register settings.

9.3 Multi Purpose I/O

The RAA215300 includes a set of multiple purpose inputs/outputs (MPIO0 to 5) with programmable functionalities.

If configured as either a Reset Output, External VR EN Output, or External VR power-good Input, during power-on/off each MPIOx has a power-on/off delay, which is set in MPIOx Power-On and MPIOx Power-Off registers. The power-on and power-off delay can be programmed from 0 to 127ms. The polarity, type, and function of each MPIOx can be configured independently by the MPIOx_Config registers. Each MPIOx can be set to either active low or active high using the register bit MPIOx_Invert. Each MPIOx can be set to general purpose input/output or a specific function. The supported functions for each pin are shown in [Table 2.](#page-38-0) When an MPIOx is set as a general purpose input, its status is read from the MPIO Input Status register. When an MPIOx is set as a general purpose output, it can be set to LOW or HIGH using the MPIO_I2C_Output register.

When an MPIOx is set to output, four different types can be selected from register bits MPIOx Type[1:0]: high impedance, open-drain NMOS output, open-drain PMOS output, or full CMOS output. When set to an open-drain NMOS output, the MPIO must be pulled up to an external voltage higher than the VIH threshold through a resistor, but within its allowable operating range. When set to open-drain PMOS output, the MPIO must be pulled down to GND through a resistor. When set to full CMOS output, the MPIO does not require an external pull-up voltage as it is pulled up to VIO internally.

It is acceptable to have multiple MPIOx configured with the same function.

The MPIOx configuration registers (0x8A - 0x8F) can be locked by the MPIO Config Lock bit to prevent the user from accidentally changing the MPIOx configurations. When this bit is set to 1, the registers at 0x8A - 0x8F are locked, which means that writing to those registers is ignored. The values in those registers can still be read back. After being set to 1, this bit cannot be set back to 0 until POR.

See the pin mapping shown in [Table 2](#page-38-0).

Function	Type	MPIO0	MPIO1	MPIO ₂	MPIO3	MPIO4	MPIO5
Unused MPIOx Pin		Yes	Yes	Yes	Yes	Yes	Yes
External VR PGOOD Input	Input	Yes	Yes	Yes	Yes	Yes	Yes
Input to I ² C Register	Input	Yes	Yes	Yes	Yes	Yes	Yes
PGOOD Output	Output	Yes	Yes	Yes	Yes	Yes	Yes
Reset Output	Output	Yes	Yes	Yes	Yes	Yes	Yes
External VR EN Output	Output	Yes	Yes	Yes	Yes	Yes	Yes
Output to I ² C Register	Output	Yes	Yes	Yes	Yes	Yes	Yes
32kHz Clock (32K CLK)	Output			Yes	٠	٠	$\overline{}$
SLEEP#	Input			٠	Yes	۰	$\overline{}$
WDT RST#	Input		\overline{a}	$\overline{}$	٠	Yes	٠
CRST IN#	Input	۰	\overline{a}	$\overline{}$	۰		Yes

Table 2. MPIOx Supported Functions

9.3.1 Unused MPIOx Pin

If an MPIO is not used, Renesas recommends setting the respective MPIO Type to Disabled (high impedance) and MPIO Function to Disabled in EEPROM. Any MPIO can be disabled. When disabled, it is high-impedance.

If the user does not want to program EEPROM when an MPIO is not used, the MPIO that is configured as an output can be left floating. The MPIO that is configured as an input must be connected to a known voltage to ensure it is in the de-assertion state.

9.3.2 External VR PGOOD Input

Any MPIO can be set to perform this function. When asserted, this signal pauses the power-on or power-off sequence timing of the RAA215300, providing a way to sequence the RAA215300 with an external regulator. The expected External VR PGOOD Input delays are set by the applicable MPIO power-on and power-off delays. Only the outputs with delay settings that are larger than the External VR PGOOD Input MPIO delay setting (relative to PWRON) are affected by the assertion or de-assertion of this MPIO input signal.

During power-on, when PWRON is asserted, the External VR PGOOD Input is expected to be asserted by the host within the delay time set in the MPIO Power-On register. If External VR PGOOD Input is not asserted before the MPIO delay expires, the power sequence pauses and waits for the signal to toggle. The delay timers of the outputs start to count when PWRON is asserted and are paused when the External VR PGOOD Input MPIO delay timer expires. When this input is asserted by the host, the power sequence continues. If External VR PGOOD Input is asserted before the MPIO delay expires, the outputs are not paused.

During power-off, when PWRON or CEN is de-asserted, the External VR PGOOD Input is expected to be deasserted within the delay time set in the MPIO Power-Off register. If External VR PGOOD Input is not de-asserted, the power sequence pauses and waits for the signal to toggle. The delay timers of the outputs start to count when PWRON or CEN is de-asserted and are paused when the External VR PGOOD Input MPIO delay timer expires. When External VR PGOOD Input is de-asserted by the host, the power sequence continues. If External VR PGOOD Input is de-asserted before the MPIO delay expires, the outputs are not paused.

When only one MPIO is set to the External VR PGOOD Input function, the power-on or power-off delay of each output is calculated using [Equation 1](#page-39-0) where t_x is the delay setting of the output, T is the time when the External VR PGOOD Input is asserted or de-asserted after PWRON is asserted or de-asserted, and t_{MPIO} is the delay setting of the External VR PGOOD Input.

(EQ. 1) $\rm{t_{delay} = t_{x} + max(0, T - t_{MPIO})}$

When multiple MPIOs are set to the External VR PGOOD Input function, the power-on or power-off delay of each output is calculated using [Equation 2](#page-39-1).

(EQ. 2) ${\rm t_{delay}} = {\rm t_x}$ +max(0, T_y – ${\rm t_{MPIOy}}$, …, T_N – ${\rm t_{MPION}}$)

MPIO0 is affected by External VR PGOOD assertion.

Figure 16. Power-On Example - External VR PGOOD Input

Figure 17. Power-Off Example - External VR PGOOD Input

9.3.3 Input to I2C Register

Any MPIO can be set to support this function. When an MPIO is set to this function, it is a general-purpose input. Its status can be read from the MPIO Input Status register.

9.3.4 PGOOD Output

Each MPIO can be configured as PGOOD output, and can be assigned to: a single regulator; VTTREF, or the AND of all regulators and VTTREF.

- When PGOOD output is assigned to a buck regulator, it is asserted when the regulator is enabled and its output voltage is greater than its undervoltage threshold and less than its overvoltage threshold.
- When PGOOD is assigned to an LDO, it is asserted when the regulator is enabled and its output voltage is greater than its undervoltage threshold.
- When PGOOD is assigned to VTTREF and VTTREF is enabled, PGOOD output is asserted IF (VREFIN > VREFIN_UVLO) AND Buck2 soft start has completed. Otherwise, PGOOD output is de-asserted.
- When PGOOD is assigned to VTTREF and VTTREF is disabled, PGOOD output is asserted. This assignment allows the PGOOD AND function to operate when VTTREF is disabled.
- If any regulator is disabled and PGOOD output is set to AND of all regulators, PGOOD is not asserted.

9.3.5 Reset Output

Any MPIO can be set to support this function. The reset output provides a system reset signal. There can be more than one reset output required in the system, including processor reset (PRST#) and eMMC reset (eRST#). Multiple MPIO can be configured as reset outputs.

The reset output is asserted as soon as the EEPROM recall is completed. During power-on when PWRON is asserted, the reset output is de-asserted after the delay time set in the MPIOx Power-On register. During power-off when CEN or PWRON is de-asserted, the reset output is asserted after the delay time set in the MPIOx Power-Off register.

9.3.6 External VR EN Output

Any MPIO can be set to support this function. This output can be used as an enable signal to control an external regulator power-on/off. It should be configured such that when asserted by RAA215300 the signal enables the external regulator, and when de-asserted it should disable the external regulator.

Any MPIOx with this function is initially de-asserted as soon as the EEPROM recall is completed. During power-on when PWRON is asserted, the VR EN Output is asserted after the delay time set in the MPIOx Power-On register. During power-off when CEN or PWRON is de-asserted, the VR_EN is de-asserted after the delay time set in the MPIOx Power-Off register.

9.3.7 Output to I2C Register

Any MPIO can be set to support this function. The MPIOx can be asserted HIGH or LOW with software control by setting the related bit in the register.

9.3.8 32kHz Clock (32K_CLK)

Only MPIO2 supports this function. The function provides a driven clock signal output for external devices. The clock frequency is programmable with a maximum setting of 32.768kHz, which is the RTC crystal oscillator frequency. The RTC must be enabled by the RTC EN bit to output this clock signal. If the user does not have an external pull-up voltage, the MPIO2 must be configured as a Full CMOS output.

When this function is selected, the MPIO2 Power-Off Delay register Bits [3:0] are used to select the clock frequency. In this case, Bits [6:0] in this register are no longer used as a power-off delay. See the [Register Map](#page-77-0).

9.3.9 SLEEP#

Only MPIO3 supports this function. This is an edge-triggered, hardware control input to control switching the device between {SLEEP} and {ACTIVE} operating states. The RAA215300 transitions from {ACTIVE} to {SLEEP} (through {ACTIVE_TO_SLEEP}) when SLEEP# is asserted, and transitions from {SLEEP} to {ACTIVE} (through {SLEEP_TO_ACTIVE}) when SLEEP# is de-asserted.

When MPIO3 is set to other functions, the sleep/active state can be controlled by software using the SLEEP State EN bit to control {SLEEP} mode entry/exit. When SLEEP State EN bit = 1, the device transitions to {ACTIVE_TO_SLEEP}, and when SLEEP_State_EN bit = 0, the device transitions to {SLEEP_TO_ACTIVE}. The hardware input and software bit control have a logical OR relationship, see [Table 3](#page-41-4). To maintain hardware control, the bit should be kept at 0, whereas to maintain bit (software) control the hardware input must internally de-assert the signal (0) as determined by the MPIO3 Invert configuration.

9.3.10 WDT_RST#

Only MPIO4 supports this function. This is a falling edge triggered input signal. When the watchdog timer is enabled, this signal is used to reset it before the timer expires. If the watchdog timer is disabled, this signal is ignored. See [Watchdog Timer](#page-43-0) for the details.

9.3.11 CRST_IN#

Only MPIO5 supports this function. The CRST_IN# input is edge triggered and acts as a hardware reset signal. When the MPIO5 Invert = Active LOW, the signal is asserted on the falling edge of MPIO5. When MPIO5 Invert = Active HIGH, the signal is asserted on the rising edge of MPIO5. The minimum pulse width requirement is 1.5µs (typical) because of internal de-glitching and synchronization to the internal clock. This signal is only valid in {ACTIVE} or {SLEEP}.

When CRST IN# is asserted:

- If currently in {SLEEP}, the RAA215300 enters {ACTIVE}. The device does not enter {SLEEP} until the reset cycle has been completed or the related latched fault has been cleared.
- The CRST_Triggered_Latched and CRST_Triggered_Live fault bits are set. INT# is pulled LOW if not masked.
- The following occurs if the CRST_Fault_EN bit = Disabled:
	- The RAA215300 enters {IORESET}. Any MPIOx configured as reset outputs are asserted immediately.
	- When CRST IN# is de-asserted by the host, the reset outputs are de-asserted following the configured power-on sequence. The CRST_Triggered fault bits cannot be cleared until CRST_IN# is de-asserted.
- The following occurs if the CRST_Fault_EN bit = Enabled:
	- Any MPIOx configured as reset outputs are asserted and the output rails are shut down following the power-off sequence configured in the register settings. RAA215300 enters {FAULT_OUT}.
	- If the latched fault bit is subsequently cleared, the device transitions to {STANDBY}.

Note: Assertion of CRST IN# is latched until the Sequencer FSM reaches {IORESET}. If CRST IN# is asserted in {ACTIVE_TO_STANDBY} or {STANDBY_TO_ACTIVE}, the FSM can not reach {IORESET} at that time. The next time the FSM reaches {ACTIVE}, it can act on the latched CRST_IN# assertion, and jumps to {IORESET}.

Figure 18. Example of CRST_IN# Operation - CRST_FAULT_EN = Disabled

9.3.12 Alternative Decodes for MPIOx functions

When an MPIO is configured as a PGOOD output, 32K CLK, or Watchdog Timer Reset (WDT_RST#), the respective MPIOx Power-On Delay or MPIOx Power-Off Delay register bits settings are changed to a different set of decodes which works for this particular function. In this case, Bits [6:0] in this register are no longer used as power-on or power-off delay. See [Table 4](#page-43-1) for details.

MPIOx and Configured Function	Register Bits	Alternative Settings for the Register Bits
MPIO0 configured as PGOOD output	MPIO0 Power-On Delay register Bits [3:0]	Set which regulator is used for PGOOD output at MPIO0
MPIO1 configured as PGOOD output	MPIO1 Power-On Delay register Bits [3:0]	Set which regulator is used for PGOOD output at MPIO1
MPIO2 configured as PGOOD output	MPIO2 Power-On Delay register Bits [3:0]	Set which regulator is used for PGOOD output at MPIO ₂
MPIO2 configured as 32K CLK	MPIO2 Power-Off Delay register Bits [2:0]	Set frequency for the 32K CLK signal
MPIO3 configured as PGOOD output	MPIO3 Power-On Delay register Bits [3:0]	Set which regulator is used for PGOOD output at MPIO3
MPIO4 configured as PGOOD output	MPIO4 Power-On Delay register Bits [3:0]	Set which regulator is used for PGOOD output at MPIO ₄
MPIO4 configured as Watchdog Timer Reset	MPIO4 Power-Off Delay register Bits [3:0]	Set timeout period for the WDT
MPIO5 configured as PGOOD output	MPIO5 Power-On Delay register Bits [3:0]	Set which regulator is used for PGOOD output at MPIO ₅

Table 4. Alternative Decodes for MPIOx Functions

9.4 Watchdog Timer

The WDT starts when the device reaches {STANDBY_TO_ACTIVE}, and is disabled again when the device reaches {STANDBY}. The function can be enabled/disabled in EEPROM.

The WDT feature can be used to detect a system boot-up failure. The function of MPIO4 must be set to WDT_RST# and the WD_EN bit must be set to 1 to enable this feature. MPIO4 Power-Off register Bits [3:0] are used to set the timeout period when MPIO4 is set to WDT_RST#. Register bits WD_PD_EN and WD_RST_EN are used to set the device behavior when the WDT feature is enabled.

The WDT_RST# input must be asserted by the host to reset the timer before it expires. If the watchdog timer expires, the RAA215300 takes the following steps:

- 1. If currently in {SLEEP}, the RAA215300 enters {ACTIVE} through {SLEEP_TO_ACTIVE}.
- 2. The WDT_Error_Latched and WDT_Error_Live fault bits are set. INT# is pulled LOW if not masked.
- 3. The following occurs if the WD_RST_EN bit = Enabled, WD_PD_EN bit = Disabled:
	- a. Any MPIOx configured as reset outputs are asserted immediately. The reset outputs are then de-asserted automatically following the power-on sequence.
	- b. The WDT stops counting when the WDT_Error fault bits are set. It does not start counting until WDT_RST# is asserted by the host. The WDT_Error fault can only be cleared by writing 1 after WDT_RST# is asserted and before the WDT expires again, or after PWRON is de-asserted.
- 4. The following occurs if the WD_PD_EN bit = Enabled:
	- a. Any MPIOx configured as reset outputs are asserted and the output rails are shut down following the power-off sequence configured in the register settings.
	- b. The WDT stops counting when the WDT Error fault bits are set. It does not start counting until the WDT Error bit is subsequently cleared by writing 1. The WDT Error fault cannot be cleared until the power-off sequence finishes and the device enters {FAULT_OUT}. When the fault is cleared, the WDT starts counting (restarts power-on sequence).

Note: If both WD_PD_EN and WD_RST_EN are set to be enabled, the WD_PD_EN bit has higher priority and WD_RST_EN is ignored.

Figure 20. Example of WDT_RST# Operation - WD_RST_EN bit = Enabled, WD_PD_EN bit = Disabled

Figure 21. Example of WDT_RST# Operation - WD_PD_EN bit = Enabled

9.5 Power Sequencing

The power sequencing starts when PWRON is asserted in {STANDBY} and the device transitions to {ACTIVE}. The RAA215300 regulators and MPIOx power-on delays are configured in the EEPROM.

The output voltage of each rail is monitored after it completes soft-start. If there is an undervoltage or overvoltage condition detected, the PGOOD output (if any MPIO is configured to this function) is de-asserted and the device enters {FAULT_OUT} (if these faults are configured to shut down the device).

9.5.1 Power-ON

The power-on delays for all rails are independently programmable from 0 to 127ms, with a 1ms step. All timing is based on entry to {ACTIVE}.

Each rail has a programmable startup slew rate.

9.5.2 Power-OFF

The power-off delays for all rails are independently programmable from 0 to 127ms, with a 1ms step. All timing is based on entry to {ACTIVE}.

Each rail has a programmable shutdown slew rate.

9.5.2.1 I2C Trigger Power-Off

The device includes a feature to trigger sequenced power-off operations triggered by an I²C command. Triggering requires sending a specific 8-bit key to the I2C_Trigger_Power_Off_Key bits.

This function is intended for use when the device is configured in long-push button mode, see [PWRON](#page-37-0).

The following are examples of power-on and power-off sequences in various configurations.

Figure 23. Typical Power-Off Example - PWRON as On/Off Switch

Figure 24. Typical Power-On Example - PWRON as Long Push Button

Figure 27. I2C Triggered Power-Off - PWRON = LOW. PWRON as Long Push Button, Active HIGH

9.6 Warm and Cold Reset

The RAA215300 features two types of software-controlled reset functions for controlling the application system (warm reset and cold reset). These resets can be separately triggered by setting the related volatile register bit to 1. Warm and cold reset bits should not be set simultaneously. When the selected reset operation is completed, the bit is automatically cleared to 0 in the volatile register.

The warm reset register bit is used to generate a system reset only. It does not recycle the RAA215300 output power rails. When triggered, the MPIO configured as reset outputs are asserted immediately. The reset signals are then de-asserted following the power-on timing set in their respective MPIOx Power-On Delay register. The LDO_SELx status may be changed because of the processor being reset, and the device responds accordingly.

The cold reset register bit generates a system reset and recycles the output power rails. When triggered, the MPIO configured as reset outputs are asserted following their power-off delay settings, and the output rails power down following their programmed sequence settings. When power-down completes, the FSM enters {STANDBY}. After a programmable delay set by the Cold Reset Delay register bits, the output rails are restarted based on their programmed sequence settings. The reset signals are then de-asserted following the power-on timing set in the respective MPIOx Power-On Delay register.

Figure 28. Warm Reset Operation

Figure 29. Cold Reset Operation

9.7 Output Discharge

There are four programmable options for the discharge of the buck rails:

- Set the regulator into Forced PWM (FPWM) mode and ramp down the reference following the programmed slew rate.
- Set the regulator into PFM/PWM mode and ramp down the reference following the programmed slew rate.
- Discharge the output rails using programmable discharge resistors. This option disables the regulator, turns the discharge switch on, and ramps down the reference following the programmed slew rate.
- Discharge the output rails using programmable discharge resistors. This option disables the regulator and turns the discharge switch on without ramping down the reference first - providing a simple RC discharge rate.

There are two programmable options for the discharge of the LDO rails:

- Discharge the output rails using programmable discharge resistors. This option disables the regulator, turns the discharge switch on, and ramps down the reference following the programmed slew rate.
- Discharge the output rails using programmable discharge resistors. This option disables the regulator and turns on the discharge switch without ramping down the reference first - providing a simple RC discharge rate.

During startup, there is no active discharge. Discharge functionality is disabled until after the state machine reaches {ACTIVE} or {ACTIVE_TO_STANDBY}. Active discharge is disabled in {RESET}.

Note: In VTT mode, check that the DDR manufacturer's recommendations are achieved during the discharge of VDDQ (typically Buck2) and VTT (Buck6).

9.8 DVS

The RAA215300 employs dynamic voltage scaling (DVS) to optimize power and efficiency in the system. The DVS features programmable DVS ramp-up/down slew rates for each rail that are applied when the output voltage(s) are changed. The common usage is to change the output voltages between {ACTIVE} and {SLEEP}. Exiting {SLEEP} often occurs to handle a real-time request; therefore, a fast slew rate is often required.

DVS is also used when changing the output voltage during {ACTIVE}. When the new output voltage is written into the register, the DVS block slews the output voltage to the new target based on the programmed rate.

[Figure 30](#page-49-0) illustrates the DVS between {ACTIVE} <-> {SLEEP} state transitions with delays.

Figure 30. {ACTIVE} <-> {SLEEP} DVS Transition Example

Note: Not all DVS rate setting options (primarily the faster rate options) for the buck and LDO rails may be attainable in certain application configurations and conditions. DVS settings program a target for the rate of change of output voltage. The maximum rate of increase for the output voltage is limited by current limit, load current, and load capacitance. The maximum rate of decrease for the output voltage is limited by load current and

load capacitance. The maximum and minimum rates of increase and decrease in the output voltage can be less than the DVS setting.

9.9 Real-Time Clock

9.9.1 Clock

The RTC is a low-power real-time clock with timing and crystal compensation, clock/calendar, power fail indicator, periodic or polled alarm, intelligent battery backup switching, and battery-backed user SRAM. The oscillator uses either an external, low-cost 32.768kHz crystal or an external clock IC. The real-time clock tracks time with separate registers for hours, minutes, and seconds. The clock format can be set to either AM/PM or 24-hour. There are calendar registers for the date, month, year, and day of the week. The calendar is accurate until 2099.

The RTC clock/calendar portion is fully operational from 1.8V to 5.5V. See [VCHG, VBAT, and VRTC](#page-33-0) for more details.

The accuracy of the real-time clock depends on the external 32.768KHz crystal or clock IC. The RAA215300 provides on-chip crystal compensation networks to adjust load capacitance to tune the crystal oscillator frequency. See [Oscillator Frequency Accuracy](#page-52-0) for details.

Figure 31. RTC Block Diagram

Note: To activate the RTC, the host must first set the RTC EN bit = 1 and the WRTC bit = 1. If using an external crystal, the XTOSCB bit must be set at 0 to enable the crystal oscillator. If using an external clock signal, set the XTOSCB bit as 1 to disable the crystal oscillator. Then, the date and time registers can be set accordingly, and the RTC is clocking and maintaining time. The clock does not increment until at least 1 byte is written to the clock/calendar registers.

INT# is a multi-functional output that can issue an interrupt or frequency signal. The function is selected by frequency out (FO) control bits. In interrupt mode, if an alarm condition occurs, the Interrupt Request (IRQ) is sent to the host processor. In Frequency Output (FOUT) mode, the output is a clock signal at a frequency generated from the crystal frequency.

The I²C interface is not functional if VIO_PGOOD is low. See [VCHG, VBAT, and VRTC](#page-33-0) for more details.

9.9.2 Alarm

The flexible alarm of the RTC can be set to any clock/calendar value for a match. For example, every minute, every Tuesday, or at 5:23 AM on March 21. The alarm status is available by checking the Status Register, or the device can be configured to provide a hardware interrupt using INT#. A backup power input (VBAT) allows the device to be powered by a battery or supercapacitor with an automatic switchover between VCHG and VBAT.

The alarm compares the alarm registers with the RTC registers. As the RTC advances, the alarm is triggered when a match occurs. The alarm is enabled by the ALME bit. There are two alarm modes: single-event mode and periodic interrupt mode.

Single-event mode is enabled by setting the ALME bit to 1, the IM bit to 0, and the FO[3:0] bits to 0000. This mode detects a one-time match between the alarm registers and RTC registers. When this match occurs, the interrupt request (IRQ) is sent to the host processor. The ALM bit is set to 1, and the INT# output is pulled low and remains low until the ALM bit is reset.

The periodic interrupt mode allows for repetitive or recurring alarm functionality. This mode is enabled by setting the ALME bit to 1, the IM bit to 1, and the FO[3:0] bits to 0000. There is an alarm each time there is a match of the alarm time and present time. Therefore, there is an alarm as often as every minute (if only the nth second is set) or as infrequently as once a year (if at least the nth month is set). During Periodic Interrupt Mode, INT# is pulled low for 250ms, and the alarm status bit (ALM) is set to 1.

Note: The ALM bit can be reset by writing 0 to it or cleared by a valid read operation in the auto reset mode. The alarm function can be enabled/disabled during battery backup mode using the FOBATB bit.

The INT# output is updated every 250ms (typical) when used as the IRQ output. The INT# output is pulled low 250ms after the alarm is triggered. After the INT# output is pulled low, it is low for at least 250ms, even if the correct action is taken to clear it. It is impossible to clear ALM if it is still active. The host must wait for the RTC to progress past the alarm time plus the 250ms delay before clearing ALM. Alternatively, the host may set ALME = 0 before clearing ALM. There is an internal delay (typically around 250µs) from setting ALME = 0 to disabling the alarm function, so the user must add a short delay of greater than 250µs between setting ALME = 0 and clearing ALM. Therefore, the host must wait for 250ms plus the short delay to detect the release of INT# after INT# is pulled low.

9.9.3 Frequency Output

A clock signal related to the oscillator frequency can output from INT# or MPIO2.

FOUT from INT# is enabled by setting FO[3:0] bits to a non-zero value. The frequency is selected using the I2C bus. See [Table 5.](#page-51-0)

FO ₃	FO ₂	FO ₁	FO ₀	FOUT from INT# (Hz)
$\mathbf 0$	Ω	Ω	0	
0	0	Ω		32768
0	Ω			4096
Ω	n			1024
0		Ω	O	64
Ω		Ω		32
⁰				16
U				8
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Table 5. Frequency Selection of FOUT at INT#

Table 5. Frequency Selection of FOUT at INT#

If enabled, a clock signal is outputted from MPIO2(see [Table 6](#page-52-1)). For detailed information about MPIO2 frequency output, see [32kHz Clock \(32K_CLK\)](#page-41-1).

Table 6. Frequency Selection of Clock Signal at MPIO2

9.9.4 General Purpose User SRAM

The RTC has 2 bytes of user SRAM, which continue to operate in battery backup mode. However, the I²C bus is disabled if VCHG falls below the AVDD UVLO falling threshold.

9.9.5 Power Control Operation

There are two power supply inputs for the RTC circuit (VCHG and VBAT). The RAA215300 contains internal circuitry to automatically switch over to the backup battery when the main VCHG supply fails and switches back from the battery to VCHG when the main supply recovers. See [VCHG, VBAT, and VRTC](#page-33-0) for details.

9.9.6 Power Failure Detection

The RAA215300 has a Real-Time Clock Failure (RTCF) bit to indicate total power failure. The RTCF bit is read-only and is set to 1 if the RTC has powered up after the failure of both VCHG and VBAT.

The bit is set regardless of whether VCHG or VBAT is applied first. At power-up after a total power failure, all registers are set to their default states, and the clock does not increment until at least 1 byte is written to the clock register. The first valid write to the RTC section resets the RTCF bit to 0.

9.9.7 Crystal Oscillator

A crystal can be used to generate the 32.768kHz clock and provide the time base for the RTC.

9.9.7.1 Oscillator Frequency Accuracy

The oscillator frequency accuracy primarily depends on the crystal accuracy and the match between the crystal and the load capacitance. If the load capacitance is too small or too large, the oscillator is too fast or too slow, respectively. RAA215300 provides an oscillator frequency adjustment mechanism that includes analog

compensation in the RTC ATR register and digital compensation in the RTC DTR register. The combination of analog and digital trimming can give a maximum range of adjustment of -80ppm to +130ppm.

Note: Both of the frequency outputs on INT# and MPIO2 are affected by the setting in the RTC ATR register. The frequency on INT# is affected by the RTC DTR setting at all frequencies except the 32.768kHz setting. The frequency on MPIO2 is not affected by the RTC DTR setting.

9.9.7.2 Crystal Oscillator Frequency Trimming

The RAA215300 provides the option of timing correction of the crystal oscillator. Analog and digital compensation mechanisms are available as follows.

9.9.7.2.1 Analog Trimming with On-Chip Load Capacitance

The analog trimming register bits (ATR[5:0]) are used to trim oscillator frequency by selecting on-chip load capacitance. There are six bits for ATR, and the selectable range is from 4.5pF to 20.25pF. The available trim range of the oscillator frequency accuracy in ppm varies with crystals, operating temperature, and the stray capacitance of the PCB. As an example, the available PPM range for an ECX-.327-CDX-1293 crystal is -20ppm to 70ppm measured on the device evaluation board at 25°C.

Figure 32. Diagram of On-Chip Load Capacitance

The on-chip load capacitance (C_{LOAD}) is the series combination of C_{X1} and C_{X2} shown in [Figure 32](#page-53-0). C_{X1} and C_{X2} range from 9pF to 40.5pF. The values of C_{X1} and C_{X2} are given in [Equation 3](#page-53-1):

(EQ. 3) $C_X = (16 \cdot \overline{b5} + 8 \cdot b4 + 4 \cdot b3 + 2 \cdot b2 + 1 \cdot b1 + 0.5 \cdot b0 + 9)$ pF

1

The series load capacitance (C_LOAD) is derived by [Equation 4:](#page-53-2)

(EQ. 4)

$$
c_{\text{LOAD}} = \frac{1}{\left(\frac{1}{C_{X1}} + \frac{1}{C_{X2}}\right)}
$$

$$
c_{\text{LOAD}} = \left(\frac{16 \cdot \overline{b5} + 8 \cdot b4 + 4 \cdot b3 + 2 \cdot b2 + 1 \cdot b1 + 0.5 \cdot b0 + 9}{2}\right) pF
$$

For example, C_{LOAD} = 12.5pF when ATR[5:0] = 000000, C_{LOAD} = 4.5pF when ATR[5:0] = 100000, and C_{LOAD} = 20.25pF when ATR[5:0] = 011111.

9.9.7.2.2 Battery Backup Mode Analog Trimming

The crystal oscillator frequency accuracy can change when the RTC is supplied by different power sources (VCHG or VBAT). The on-chip load capacitance offset between VCHG mode (VRTC supplied by VCHG) and battery backup mode (VRTC supplied by VBAT) is adjustable by BMATR[1:0]. The available range is from -0.5pF to 1pF.

9.9.7.2.3 Digital Trimming

The oscillator frequency is also affected by the digital trimming bits DTR[2:0] in the RTC DTR register. The DTR trim setting modifies the divider stage in the RTC digital block. The available trim range is from -60ppm to +60ppm. It is used for coarse adjustments of frequency drift over temperature or extending the adjustment range provided by the ATR settings.

9.9.7.2.4 Crystal Oscillator Frequency Adjustment

The Initial accuracy of the crystal oscillator can be adjusted by enabling the frequency output on INT# and monitoring it with a calibrated frequency counter. The gating time on the counter should be set long enough to ensure the accuracy of the reading. The ATR[5:0] bits can be set to 000000, to begin with. After the initial measurement is made, the RTC ATR register can be changed to tune the frequency. If the initial measurement shows the frequency is far off, then the DTR[2:0] can be used to do a coarse adjustment. Most crystal oscillators have tight enough accuracy at room temperature that the RTC ATR register adjustment should be all that is required.

9.9.7.3 Temperature Compensation

The external crystal temperature drift is progressively worse as the crystal temperature deviates from +25°C. [Figure 33](#page-54-0) shows an example of temperature drift characteristics. There is a turnover temperature (T0) where the drift is near zero. The shape is parabolic because it varies with the square of the difference between the actual temperature and the turnover temperature.

Figure 33. RTC Crystal Temperature Drift Example

A possible system to implement temperature compensation would consist of the RAA215300, a temperature sensor, and a microcontroller. These devices may already be in the system, so the function could just be a matter of implementing software and performing some calculations. Fairly accurate temperature compensation can be implemented just by using the crystal specifications for the turnover temperature T0 and the drift coefficient (β) . [Equation 5](#page-54-1) is used to calculate the oscillator adjustment necessary,

(EQ. 5) Adjustment(ppm) = $(T - T_0)^2 * \beta$

When the temperature curve for a crystal is established, the designer should decide at what discrete temperatures the compensation changes.

A sample curve of the ATR[5:0] setting vs Frequency Adjustment for the RAA215300 and a typical RTC crystal is given in [Figure 34](#page-55-0). This curve may vary with different crystals and PCBs, so it is good practice to evaluate a given crystal in the RAA215300 circuit before establishing the adjustment values. The curve is then used to determine ATR[5:0] and DTR[2:0] settings. The results could be placed in a lookup table for the micro-controller to access.

Figure 34. ATR Setting Vs. Crystal Oscillator Frequency Adjustment

9.9.8 Using an External Clock

The RTC can use either a standard 32.768kHz crystal or an external clock. VBAT must be valid when using an external clock. XIN can be programmed for connection to an external clock input using the XTOSCB bit in the RTC SR register. When this bit is set to 1, the oscillator is disabled and XIN is a CMOS-compatible clock input.

The external clock input must be logic level CMOS (0.3 x VBAT LOW, 0.7 x VBAT HIGH), square wave preferred, frequency = 32.768KHz. The clock voltage must not exceed VBAT.

To check if the external clock is working properly, the following methods can be used to check the RTC function:

- Poll the time register to make sure the seconds are advancing at the correct rate.
- Enable the frequency on INT# or MPIO2: Clock and monitor the frequency for the correct value.

9.9.9 Real-Time Clock Registers

9.9.9.1 Clock and Calendar Registers [Address 0x00 to 0x06]

Time is set in BCD format by the following registers:

- RTC SC and RTC MN registers: Sets seconds and minutes that range from 0 to 59.
- RTC HR register: Sets hour that ranges from 0 to 23 or 1 to 12.
- RTC DT register: Sets date that ranges from 1 to 31.
- RTC MO register: Sets month that ranges from 1 to 12.
- RTC YR register: Sets year that ranges from 0 to 99.
- RTC DW register: Sets day of the week that ranges from 0 to 6.

See [Register Map Detail](#page-77-1) for bits decoding.

A 12-hour or 24-hour format can be set by the MIL bit. If it is set to 1, the RTC uses a 24-hour format. If it is set to 0, the RTC uses a 12-hour format. In this case, the HR21 bit functions as an AM/PM indicator with 0 representing AM and 1 representing PM. The clock defaults to a 12-hour format time with HR21 = 0.

Note: To maintain correct month and date registers, the host must force the RTC MO and RTC DT registers to the correct values in specific years, as shown in [Table 7.](#page-56-0)

Year	Action Required by the Host
00/04/08/20/24/28/40/44/48/60/64/68/80/84/88	Force the RTC MO register to 00011 (March) after 11:59:59pm on February 29
10/14/18/30/34/38/50/54/58/70/74/78/90/94/98	Force the RTC MO register to 00011 (March) and RTC DT register to 000001 (date 01) after 11:59:59pm on February 28
12/16/32/36/52/56/72/76/92/96	Force the RTC MO register to 00010 (February) and RTC DT register to 101001 (date 29) after 11:59:59pm on February 28

Table 7. Actions Required by the Host in Specific Years

9.9.9.2 Control and Status Registers [Address 0x07 to 0x0B]

9.9.9.2.1 RTC Status Register (RTC SR)

This is a volatile register that sets RTC functions and reports status. The following sections detail each bit.

Real-Time Clock Fail Bit (RTCF)

This read-only bit is set to 1 by the device after a power failure where both VCHG and VBAT lose power. After a power failure, all registers are set to their default states when the device powers up again. The host must reactivate the RTC. The first valid write operation to the RTC registers after a power failure resets the RTCF bit to 0.

Battery Bit (BAT)

This bit is set to 1 by the device when the RTC enters battery backup mode. When VCHG is valid again, this bit can be reset either by the host (by writing 0 to it) or automatically reset if ARST = 1.

Alarm Bit (ALM)

This bit is set to 1 if the alarm matches the real-time clock. It can be reset to 0 by the host (by writing 0 to it) or automatically reset if ARST = 1. Writing 1 to this bit is not accepted.

If the ALM bit is set during an RTC SR register reading operation, it remains set after the reading operation is complete.

Write RTC Enable Bit (WRTC)

The WRTC bit enables or disables writing capability into the RTC clock and calendar registers. The factory default setting of this bit is 0. On initialization or power-up, the WRTC bit must be set to 1 to enable the RTC. At the completion of a valid write command (STOP), the RTC starts to count. The RTC internal 1Hz signal is synchronized to the STOP condition during a valid write cycle.

Crystal Oscillator Enable Bit (XTOSCB)

This bit enables/disables the internal crystal oscillator. When XTOSCB is set to 1, the oscillator is disabled, and XIN allows for an external 32.768kHz clock signal to drive the RTC. The XTOSCB bit is set to 0 on power-up.

Auto Reset Enable Bit (ARST)

This bit enables/disables the automatic reset of the BAT and ALM status bits only. When the ARST bit is set to 1, these status bits are automatically reset to 0 after a valid read operation of the respective status register (with a valid STOP condition). When ARST is set to 0, the host must reset the BAT and ALM bits.

9.9.9.2.2 RTC Interrupt Control Register (RTC INT)

This register can be used to control the frequency output and alarm function.

Frequency Out Control Bits (FO[3:0])

These bits enable/disable the Frequency Output function (FOUT) and select the output frequency at INT#. The selectable frequency is listed in [Table 5.](#page-51-0) When the frequency mode is enabled, it overrides the alarm mode at INT#.

Frequency Output and Interrupt Bit (FOBATB)

This bit enables/disables the IRQ/FOUT function during battery backup mode (that is, VBAT power source active). When FOBATB is set to 0, both the Frequency Output and alarm output functions are disabled. When FOBATB is set to 1, the IRQ/FOUT function is enabled during battery backup mode.

Oscillator Bias Current Control Bit (LPMODE)

With LPMODE = 0, the device works with a normal oscillator bias current. With LPMODE = 1, the device works with a reduced oscillator bias current. Renesas does not recommend setting this bit to 1.

Alarm Enable Bit (ALME)

This bit enables/disables the alarm function. When the ALME bit is set to 1, the alarm function is enabled. When ALME is set to 0, the alarm function is disabled. The alarm function can operate in either single-event mode or periodic interrupt mode. See [Alarm](#page-51-1) for more details.

Note: When the frequency output mode is enabled, the alarm function is disabled.

Interrupt/Alarm Mode Bit (IM)

This bit is used to select single-event mode or periodic interrupt mode. See [Alarm](#page-51-1) for more details.

9.9.9.2.3 Trimming Registers RTC ATR and RTC DTR

Analog Trimming (ATR[5:0])

ATR[5:0] bits are used to trim the oscillator frequency by adjusting the on-chip load capacitance value. The on-chip load capacitance value ranges from 4.5pF to 20.25pF in 0.25pF steps. See [Analog Trimming with](#page-53-3) [On-Chip Load Capacitance](#page-53-3) for more details.

Battery Mode ATR Selection (BMATR [1:0])

BMATR[1:0] bits are used to set the on-chip capacitance offset between VCHG mode and battery backup mode. See [Battery Backup Mode Analog Trimming](#page-53-4) for more details.

Digital Trimming (DTR [2:0])

DTR[2:0] bits are used to trim the oscillator frequency by modifying the digital stage in RTC. See [Digital Trimming](#page-54-2) for more details.

9.9.9.3 Alarm Registers Addresses [0x0C to 0x11]

The alarm register bytes are mapped identical to the RTC register bytes, except that the MSB of each byte functions as an enable bit (1 means enabled). These enable bits specify which alarm registers are used to make the comparison. *Note:* There is no alarm byte for year.

The followings are examples of using single-event mode and periodic Interrupt mode.

Example 1 – Alarm set to single-event mode (IM = 0)

A single-event alarm occurs on January 1 at 11:30 am.

Table 8. Register Settings in Example 1 (Cont.)

1. X can be set to either 0 or 1 depending on the application.

After these registers are set, an alarm is generated when the RTC advances to exactly 11:30 am on January 1 (after seconds change from 59 to 00) by setting the ALM bit in the status register to 1 and also pulling the INT# output low.

Example 2 – Alarm set to periodic interrupt mode (IM = 1)

An interrupt occurs every minute when the value of the RTC SC register is at 30 seconds.

Register Name	Bit 7	Bit 6	Bit 5	Bit 4	Bit 3	Bit 2	Bit 1	Bit 0	Value	Description
RTC SCA		0		1	0	Ω	0	Ω	$0 \times B0$	Seconds set to 30, enabled
RTC MNA	Ω	0	Ω	Ω	0	0	0	Ω	0×00	Minutes disabled
RTC HRA	Ω	Ω	0	Ω	0	0	0	Ω	0×00	Hours disabled
RTC DTA	Ω	Ω	$\mathbf{0}$	Ω	0	Ω	0	Ω	0×00	Date disabled
RTC MOA	Ω	0	Ω	Ω	0	Ω	0	Ω	0×00	Month disabled
RTC DWA	Ω	0	Ω	Ω	0	Ω	0	Ω	0×00	Day of week disabled
RTC INT	1		$X^{[1]}$	$X^{[1]}$	0	0	0	0	$0 \times X0$	Enable periodic interrupt mode

Table 9. Register Settings in Example 2

1. X can be set to either 0 or 1 depending on the application.

When the registers are set, the following waveform is seen at INT#. The status register ALM bit is set each time the alarm is triggered. See [Alarm](#page-51-1) for details about clearing the ALM bit.

Figure 35. Periodic Interrupt Alarm Signal

9.10 Coin Cell Battery Charger

RAA215300 features a constant current charger to charge an external backup energy storage device to maintain power to the RTC when the VCHG supply falls. A typical energy storage device is a coin cell battery or supercapacitor connected to VBAT. The charger charges the external storage device when VCHG is higher than VBAT.

The charger is always off by default (after power-on or device reset) and must be enabled by I²C.

The charger supports selectable 20µA or 60µA (typical) charge currents. If the charger is enabled and VCHG is higher than VBAT, the charge current is supplied through VBAT. The charging termination voltage is selectable by I 2C from 1.8V to 3.3V in 100mV steps.

The device does not automatically re-enable the charger when the voltage on the external storage device falls. The host should monitor the PGOODCCBAT fault bits (poll the register using P^2C) to decide if and when the charger must be re-enabled to charge up the external storage device.

The battery sense comparator is disabled by default, and the PGOODCCBAT live bit stays at 0. The sense comparator is automatically enabled when the charger is enabled. The host can check the battery status by trying to enable the charger (writing 1 to CC Charger EN bit) every certain period of time (depending on the battery backup time), and the following occurs when the device receives the command:

- If VBAT voltage is above or at the target level (charging termination voltage), the charger is not turned on and CC Charger EN bit remains at 0.
- If VBAT voltage falls below the target level, the comparator and charger are enabled. The PGOODCCBAT live and latched bits are set. INT# is asserted if not masked.

The PGOODCCBAT latched bit can be cleared by writing 1 to it. This bit is edge sensitive. When cleared, it does not set until the next time VBAT falls below the target level. When VBAT reaches the target level, the charger and comparator are automatically disabled, and the PGOODCCBAT live bit is cleared, indicating VBAT PGOOD was attained.

9.10.1 Supercapacitor Backup Time

The supercapacitor backup time is calculated using [Equation 6](#page-59-0) where C_{BAT} is the capacitance value of the supercapacitor, V_{BAT} is the battery voltage level when it is fully charged, V_{BAT} is the voltage level when the battery must recharge, and I_{BAT} is the supply current drawn from the supercapacitor.

$$
\textbf{(EQ. 6)} \qquad \text{T}_\text{Backup}(\text{seconds}) = \text{C}_\text{BAT} \times \frac{\text{V}_{\text{BAT1}} - \text{V}_{\text{BAT2}}}{\text{I}_{\text{BAT}}}
$$

For example, if C_{BAT} = 0.1F, V_{BAT1} = 3V, V_{BAT2} = 1.8V, and I_{BAT} = 950nA (maximum) when RTC is clocking, the battery backup time is 126316 seconds which equals 35 hours, which means that the host must check the battery status every 35 hours.

Charging time is calculated using [Equation 7](#page-59-1) where I_{Charge} is the charge current set in the register.

$$
\textbf{(EQ. 7)} \qquad \text{T}_{\text{Charge}}(\text{seconds}) = \text{C}_{\text{BAT}} \times \frac{\text{V}_{\text{BAT1}} - \text{V}_{\text{BAT2}}}{\text{I}_{\text{Charge}} - \text{I}_{\text{BAT}}}
$$

In the previous example, if $I_{Charce} = 60\mu A$, the charge time is 2032 seconds which equals 0.56 hours.

Note: These examples provide an approximate estimation of the battery backup time and charging time. For precise results, characterize the supply current in relation to the voltage of the supercapacitor or coin-cell battery used in the system.

9.11 Buck Regulators

The RAA215300 has six synchronous buck regulators. Internal compensation is employed to simplify application design, reduce PCB space, and reduce the BOM cost. Each buck regulator has its own programmable output range, soft-start, power-up/down timing, switching frequency, and can be individually disabled by the register and EEPROM settings. Some of the buck regulators are optimized to support various DDR memory specifications but can also be used for general purposes. The buck regulators have various output voltage ranges and current ratings, allowing the system to be flexibly designed for improved performance, such as efficiency and voltage ripple. The buck regulators can be automatically reconfigured (by register settings) between {ACTIVE} and {SLEEP} for different applications or different power requirements.

The buck regulators have two operating modes: Auto PFM/PWM and FPWM. Each buck regulator can be set to the ultrasonic mode when operating in PFM (see [Ultrasonic Mode](#page-61-0)) and can use a spread spectrum feature (see [Spread Spectrum\)](#page-62-0). A synchronous phase delay feature allows the switching of each buck regulator to be shifted in phase relative to the internal clock, which may improve EMC.

The buck regulators support Dynamic Voltage Scaling (DVS) with programmable ramp-up/down rates (see [DVS\)](#page-49-1), and offer various active discharge options (see [Output Discharge](#page-49-2)). Various warnings and faults are monitored and reported (see [Device Monitors, Warnings, and Protections\)](#page-64-0).

Note: All buck supplies (BUCKx_VINx) = AVDD = VCHG.

9.11.1 Buck1

Buck1 supports the processor or SoC core power. It provides high efficiency, fast load transient response, and low ripple voltage. It can provide up to 5A. The output voltage can be set to 1.03V, and from 0.8V to 1.5Vin 50mV steps. *Note:* The switching frequency should be reduced when using outputs 1.03V and lower.

Buck1 supports high-current warning interrupt if the output current exceeds the programmable Buck1 High Current Threshold. It can be used as an early indicator for system thermal control. It is particularly helpful during the system design phase.

Buck1 configuration details are in registers 0x20 to 0x26.

9.11.2 Buck2

Buck2 supports DDR memory VDDQ rail. It can provide up to 1.5A. The output voltage can be set from 1.1V to 1.85V, in 50mV steps. If Buck2 powers DDR memory and VTT is required, connect VREFIN to the Buck2 output rail externally.

Buck2 configuration details are in registers 0x27 to 0x2D.

9.11.3 Buck3

Buck3 can provide up to 1.5A. The output voltage can be set from 1.8V to 3.3V, in 100mV steps. It can be used to power 1.8V or 3.3V I/O or other loads.

Buck3 configuration details are in registers 0x2E to 0x34.

9.11.4 Buck4

Buck4 can provide up to 3.5A. The output voltage can be set to 0.8V, 0.85V, 0.9V, 0.95V, 1.0V, 1.05V, 1.1V, 1.15V, 1.2V, 1.5V, 1.6V, 1.8V, 1.85V, 2.2V, 2.5V, or 3.3V. It can be used to power 1.8V or 3.3V I/O or other general loads. *Note:* Reduce the switching frequency when using outputs 1.6V and lower.

Buck4 configuration details are in registers 0x35 to 0x3B.

9.11.5 Buck5

Buck5 is a regulator for system peripherals such as WiFi or Ethernet. It can provide up to 0.6A. The output voltage can be set to 1.2V, 1.5V, 1.6V, 1.8V, 1.85V, 2.2V, 2.5V, or 3.3V. It can support up to 0.6A for outputs lower than 2.5V. When the set output voltage is 2.5V or 3.3V, the maximum load current capability derates.

Buck5 configuration details are in registers 0x3C to 0x42.

9.11.6 Buck6

Buck6 supports DDR VTT, which is required to sink (receive) and source (supply) currents up to ±1A. When the VTTREF EN bit = 1, Buck6 is configured for the DDR VTT application (VTT mode). The output voltage tracks the VREFIN input and the output voltage is fixed at VREFIN/2. The power-up/down sequence tracks the VREFIN per DDR memory specification. *Note:* Sink and source currents derate when the output voltage is 0.7V and higher. Also, sink currents and/or maximum input voltage derate when the output voltage is 0.575V or lower.

Buck6 configuration details are in registers 0x43 to 0x49.

9.11.7 Buck Operating Modes

The operating mode (Auto PFM/PWM and FPWM) is set by the Buckx_ACTIVE and Buckx_SLEEP registers.

In Auto PFM/PWM mode, the buck regulator transitions between PFM and PWM modes depending on load current. At light load, it enters PFM to reduce power consumption. As load current increases, the regulator transitions to PWM. PFM mode produces higher output voltage ripple than PWM mode. FPWM produces the lowest output voltage ripple at light load but it increases quiescent current.

FPWM mode makes the regulator operate at a fixed switching frequency, as programmed in EEPROM, irrespective of the load current. At light load, there is a negative inductor current (the current flows from output capacitance, through the inductor and low-side switch).

All bucks soft-start in PFM/PWM mode, irrespective of the mode setting. After soft-start completion, if selected, the device transitions to FPWM 300µs. The regulator is unable to create a negative inductor current until FPWM mode is established.

9.11.8 Ultrasonic Mode

Ultrasonic mode is an optional feature (set in EEPROM) of each buck regulator. Its purpose is to prevent PFM switching frequency from being within the audio frequency band.

9.11.9 Unused Buck

If a buck regulator is not required in a given application, configure that unused buck as follows:

- BUCKx_VINx = Always connect to the same supply as AVDD
- BUCKx_LXx = Open
- BUCKx_FB = GND
- Disable the BUCKx block in EEPROM by both Buckx_EN_ACTIVE and Buckx_EN_SLEEP bits.

A UV fault is triggered at startup if a buck regulator is enabled in the register settings but configured as unused on the board. The fault protection function is configured in the default settings to shut down all the outputs when a UV fault is detected. To avoid shutdown, disable the unused bucks in the EEPROM settings or before asserting PWRON.

When VTTREF_EN = Enabled and the register bit Link_Buck6_to_Buck2 is set to 1, Buck6 and Buck2 start up and shut down simultaneously, and settings of the following register bits are ignored: Buck6_EN_ACTIVE, Buck6_EN_SLEEP, Buck6_Power_On_Delay, and Buck6 Power_Off_Delay. When Link_Buck6_to_Buck2 is set to 0, sequencing of Buck6 and Buck2 is independent.

If VTTREF_EN = Enabled and Buck6 is unused, Link_Buck6_to_Buck2 must be set to 0.

9.11.10 Switching Frequency

The PWM switching frequency (f_{SW}) for each buck is programmable. Changing this setting on the fly using ${}^{12}C$ is not recommended. It is preferred to change the frequency only when the output is disabled, or before PWRON assertion. See the [Register Map](#page-77-0) for the available options for each regulator and default selections.

At the load where control changes from PFM to PWM, the switching frequency is not as high as its setting. As load increases, the switching frequency increases. The setting is a maximum.

9.11.11 Spread Spectrum

To improve EMC, spread spectrum operation is optional in each buck regulator. The switching frequency is modulated to reduce peak noise power.

9.11.11.1 PFM mode

The switching frequency depends on load current and peak switch current limit. A 10-bit pseudo-random pattern is applied to the peak switch current limit code to modulate the PFM switching frequency. The PFM spread spectrum modulation rate is adjusted using the 2-bit code Buck# PFM AM[1:0].

Each buck regulator has a bit to enable/disable PFM spread spectrum operation.

9.11.11.2 PWM Mode

There are two spread spectrum modulation schemes in PWM mode: pseudo-random and triangular, set by the SS PWM_Mod bit. The 2-bit code PWM_AM[1:0] sets the amplitude of modulation. The PWM_AM bits can also be set to disable the PWM spread spectrum. The selected modulation scheme and modulation amplitude are applied to all buck regulators.

The pseudo-random scheme is implemented similarly to PFM spread spectrum modulation, but instead of modulating PFM current limit it directly modulates switching frequency. The modulation frequency is set by the 2-bit code Freq_SS[1:0]. The modulation rate is adjusted using the 2-bit code PWM_AM[1:0].

When the triangular modulation profile is selected, the PWM switching frequency is the center frequency (f_{CENTER}). A maximum frequency (f_{MAX}) and minimum frequency (f_{MIN}) are adjusted by the modulation amplitude 2-bit code PWM_AM[1:0]. The modulation frequency (f_{MOD}) is set by the 2-bit code Freq_SS[1:0].

9.11.12 Phase Synchronization

The phase relationships between the starts of switching cycles of different buck regulators can be programmed. The programmed switching frequencies of synchronized buck regulators must be the same, double, or half. When programmed, synchronization occurs when the buck regulators are running at the full switching frequency, which occurs at all loads in FPWM mode and at moderate to high load in Auto PFM/PWM mode. Phase synchronization can improve EMC.

9.12 LDO Regulators

The RAA215300 has three LDO regulators, each with programmable output voltage, soft-start timing, and power on/off delay. Each can be disabled by the register and EEPROM settings. The LDOs support various DDR memory specifications, but can also be used for general purposes. The LDOs can be reconfigured by programmed settings during transitions between {ACTIVE} and {SLEEP}. In {ACTIVE}, hardware inputs (see [LDOx Selection Inputs\)](#page-63-0) can change the output voltages of LDO1 and LDO2 at rates determined by DVS settings and limitations caused by current limit, load current, and load capacitance.

DVS settings program a target for the rate of change of output voltage. The maximum rate of increase of output voltage is limited by current limit, load current, and load capacitance.

The maximum rate of decrease of output voltage during DVS is limited by load current and load capacitance.

The maximum rates of increase and decrease in the output voltage can be less than the DVS setting.

The LDO regulators offer various active discharge options (see [Output Discharge\)](#page-49-2) at power-off. Various types of LDO regulator faults are monitored and reported, see [Device Monitors, Warnings, and Protections](#page-64-0).

The maximum rate of decrease of output voltage during a shutdown is limited by load current, load capacitance, and active discharge setting.

9.12.1 LDO1/2

LDO1 and LDO2 use the same design. The output voltages can be set to 0.8V, 0.9V, 1.2V, 1.5V, 1.8V, 2.5V, 3.0V, and 3.3V. The output voltages for {ACTIVE} and {SLEEP} are separately programmable. These LDOs support SD card interface applications.

- LDO1 configuration details are in registers 0x4A to 0x4E.
- LDO2 configuration details are in registers 0x4F to 0x53.

9.12.1.1 LDOx Selection Inputs

The LDO_SELx inputs can change the output voltages while in {ACTIVE}. For example, this can be useful when the LDOs power an SD card interface.

- When LDO SELx = HIGH, the LDOx Vo_1_ACTIVE setting is selected.
- When LDO_SELx = LOW, the LDOx_Vo_0_ACTIVE setting is selected.

LDO SELx inputs are ignored during {SLEEP}, when powering on, or during transitions from {STANDBY} to {ACTIVE}.

9.12.2 LDO3

LDO3 output voltage can be set to 0.8V, 0.9V, 1.2V, 1.5V, 1.8V, 2.5V, 3.0V, and 3.3V. The output voltages for {ACTIVE} and {SLEEP} are separately programmable. LDO3 can provide power for the DDR memory VPP rail.

9.12.3 LDOx Bypass

Each LDO can be set in bypass mode where the input and output are internally connected through the enhanced pass MOSFET.

The LDO cannot be switched in or out of bypass mode between {ACTIVE} and {SLEEP}.

9.12.4 Unused LDOx

If an LDO regulator is not required in a given application, configure that unused LDO as follows:

- LDOx_VIN = GND
- LDOx_OUT = GND
- LDO SEL1 = GND if LDO1 is not used
- LDO_SEL2 = GND if LDO2 is not used
- Disable the LDOx block in EEPROM by both LDOx EN_ACTIVE and LDOx_EN_SLEEP bits.

A UV fault is triggered at startup if an LDO is enabled in the register settings but configured as unused on the board. The fault protection function is configured in the default settings to shut down all the outputs when a UV fault is detected. To avoid shutdown, disable the unused LDOs in the EEPROM settings or before asserting PWRON.

9.13 VTTREF

The VTTREF block provides the VTT reference voltage in DDR applications. VREFOUT = VREFIN/2.

In DDR applications, VREFIN is connected to the VDDQ rail, which is typically generated by Buck2.

When Buck6 is set to VTT mode, Buck6 output provides an active tracking termination voltage (VTT) equal to VREFOUT.

If VTTREF EN = Enabled, VTTREF is enabled when Buck2 starts up and is disabled when Buck2 shuts down. VREFIN (the input to VTTREF) can be connected to the output of any of the regulators, or to any voltage source. VREFIN UVLO detection is active only after Buck2 completes soft-start and before Buck2 starts power-down.

When VREFIN UVLO is active, UVLO latched fault and live fault bits are set and all outputs shut down if VREFIN is less than its falling UVLO threshold for longer than the [VREFIN](#page-65-0) UVLO Falling Delay period. See VREFIN [UVLO.](#page-65-0)

VTTREF is enabled and disabled simultaneously with Buck2. Therefore, Buck6 must not start up earlier than Buck2 and must not shut down later than Buck2. During startup, VREFIN must be greater than two times the Buck6 output voltage, or Buck6 OV could be triggered. Many things affect the rise times. In FPWM, constraints of minimum on-time and switching frequency can make Buck6 output voltage rise quickly. Therefore, it is necessary to make VREFIN establish quickly or before Buck6. During shutdown, the voltage source connected to VREFIN cannot shut down earlier than Buck6, or Buck6 OV could be triggered.

9.13.1 Unused VTTREF

If VTTREF is not going to be configured for use as a reference for Buck6, configure the schematic and board design as follows:

- \cdot VRFFIN = GND
- VREFOUT = GND
- Disable the VTTREF block in EEPROM.

9.14 Pre-bias Startup

In some use cases, the output capacitor/load of the regulator may have residual charge and therefore a non-zero output voltage when the device is (re)started (that is, pre-biased). The RAA215300 supports pre-biased start-up.

9.15 Device Monitors, Warnings, and Protections

The RAA215300 has various monitors, warnings, and fault protection features.

If a fault is detected during normal operation, both a latched (sticky) and a live fault status bit are set. INT# is asserted if the fault interrupt is supported and not masked out. Certain fault events can be configured to shut down all rails (enter {FAULT_OUT}), or to keep all rails operating (do not enter {FAULT_OUT}). A latched fault bit remains set until cleared by the host writing a 1 to the latched register bit after the event has subsided. The live status bits show the real-time condition and indicate if the fault has subsided or persists. For more information see [Interrupt](#page-66-0) and [Fault and Status Monitoring](#page-66-1).

If a fault event shuts down the RAA215300 power rails, all the reset outputs are asserted and the output rails are powered down following the power-off sequence.

9.15.1 Input Voltage Monitor (AVDD Undervoltage Power Down)

To help prevent uncontrolled power-down due to input power loss, an AVDD voltage monitor option is included to provide the host an early warning. It is also called the AVDD Undervoltage Power Down (UVPD) feature, which has a programmable threshold and can be enabled/disabled in the EEPROM. When the programmed threshold is reached, after a delay the AVDD_UVPD_Latched and AVDD_UVPD_Live status bits are set and, if not masked, INT# is asserted. The device powers down according to the power-down sequence and then enters {FAULT_OUT}. At power-on, the device remains in {STANDBY} until AVDD exceeds the UVPD setting if the AVDD UVPD feature is enabled, and stays in this state indefinitely if AVDD remains below its UVPD setting.

The threshold options are:

- 4.25V (for 5V systems)
- 3.0V (for Li-Ion battery systems)
- 2.7V (for 3V systems)

9.15.2 AVDD UVLO

The AVDD input supply has UVLO protection. This checks the power supply is valid for normal operation. See the [Electrical Specifications](#page-10-0) for detailed specifications. When AVDD is below its UVLO falling threshold, the device enters {RESET}. See [Operating {States} and Transition Conditions](#page-34-0) for more details.

9.15.3 VREFIN UVLO

The VREFIN input has UVLO protection. When VREFIN is below its UVLO falling threshold, after a delay the VREFIN_UVLO_Latched and VREFIN_UVLO_Live fault bits are set and, if not masked, INT# is asserted. The device powers down according to the power-down sequence if it is configured to shut down all the rails by the VREFIN_UVLO_Disable bit and then enters {FAULT_OUT}.

Note: The device can be configured to either shut down all the rails or not shut down any rails by register bit VREFIN_UVLO_Disable. If the device is configured to not shut down any rails, the fault cannot be cleared until VREFIN exceeds its UVLO rising threshold. If the device is configured to shut down all the rails, the fault cannot be cleared until the power-off sequence completes.

The VREFIN UVLO Falling Delay timer is enabled after Buck2 finishes soft-start and before Buck2 starts shutdown.

Figure 36. VREFIN UVLO Fault Detection at Power-On

9.15.4 Over-Temperature Warning and Protection

The RAA215300 continuously monitors its die temperature and responds at two thresholds. The lower threshold provides a warning that the temperature is near but less than the higher protection threshold.

The thermal warning threshold is programmable. When the warning threshold is reached, a latched fault flag and live status bit are set and if not masked, it asserts INT#. When the thermal shutdown threshold is reached, a latched fault flag and live status bit are set, INT# is asserted (if not masked), and the device powers down following the power-off sequence and it enters {FAULT_OUT}.

Note: OTP_WARN_Latched fault is edge triggered, that is, when the latched fault is cleared, it is only set again when the live fault goes LOW to HIGH. OTP Latched fault is level triggered, that is, when the latched fault is cleared, it is set again if the live fault is high.

9.15.5 High Current Warning

Buck1 features a high-current warning with a programmable threshold. This can be used by the system, possibly in conjunction with the over-temperature warning, to moderate processor activity to avoid high-temperature operation. When Buck1 output current is higher than the threshold set in Buck1_High_Current_Threshold register bits, the Buck1_HC_Latched and Buck1_HC_Live bits are set, and INT# is asserted (if not masked). The device remains operating in this condition.

9.15.6 Overvoltage and Undervoltage Protection

All buck regulators have undervoltage (UV) and overvoltage (OV) fault protection. The LDOs have UV protection. PMIC response to a fault is configurable and can include assertion of INT#. When UV or OV protection threshold is reached, a latched fault flag and live status bit are set, and INT# is asserted (if not masked). If the UV Disable or OV Disable bit of the regulator is configured to shut down all the rails, the device powers down following the power-off sequence and enters {FAULT_OUT}. If it is configured to not shut down any rails, the device remains operating.

Note: The LDOx live status bits are PGOOD live status, and they are monitored when the related LDO is enabled and disabled. The LDOx latched status bits are UV latched status and are only monitored when the related LDO is enabled. Similarly, the BUCKx UV and OV status are only monitored when the related buck regulator is enabled. The INT# status depends on the latched fault status.

9.15.7 Interrupt

The RAA215300 has an interrupt (INT#) pin, which is an open-drain, active low output that can notify the system/host of a PMIC fault or alarm condition. Each latched fault can be configured to be unmasked or masked with respect to INT#. Unmasked faults assert INT#; masked faults do not. *Note:* The host can read latched and live faults from the status registers.

It is the responsibility of the host to de-assert/release INT# by clearing the latched fault bit(s). If INT# is not de-asserted, it is unable to notify the host of further qualifying events.

9.15.8 Fault and Status Monitoring

The RAA215300 supports numerous interrupt qualifying events and numerous status flags. Different fault events may have associated latched flags, live flags, and the ability to assert the INT# and power down all outputs (enter {FAULT_OUT}).

Note: Latched and live fault bits can be polled by the host at any time to check status. A latched fault sets the related flag to 1, and this remains until cleared by the host. The fault is re-triggered if the fault condition persists.

See [Table 10](#page-66-2) for a summary of all fault and status flags, see the [Register Map](#page-77-0) for all details of the bits summarized.

Fault Register Partitioning	Fault/Status Name	Live Bit Status	Latched Bit Status	INT# Mask Option	Fault Response Option	Deglitch Time (ms)	Notes
Fault 1	Buck6 UV	Yes	Yes	Yes	Yes		
	Buck5 UV	Yes	Yes	Yes	Yes		
	Buck4 UV	Yes	Yes	Yes	Yes		
	Buck3 UV	Yes	Yes	Yes	Yes		
	Buck2 UV	Yes	Yes	Yes	Yes		
	Buck1 UV	Yes	Yes	Yes	Yes		

Table 10. Fault and Status Flags: Behavior and Partitioning

Fault Register Partitioning	Fault/Status Name	Live Bit Status	Latched Bit Status	INT# Mask Option	Fault Response Option	Deglitch Time (ms)	Notes
	VIO_PGOOD	Yes	Yes	Yes	No	1	
	LDO3 UV	Yes	Yes	Yes	Yes	$\mathbf{1}$	
Fault 2	LDO ₂ UV	Yes	Yes	Yes	Yes	$\mathbf{1}$	
	LDO1 UV	Yes	Yes	Yes	Yes	$\mathbf{1}$	
	Buck6 OV	Yes	Yes	Yes	Yes	1	
	Buck5 OV	Yes	Yes	Yes	Yes	1	
Fault 3	Buck4 OV	Yes	Yes	Yes	Yes	1	
	Buck3 OV	Yes	Yes	Yes	Yes	$\mathbf{1}$	
	Buck2 OV	Yes	Yes	Yes	Yes	$\mathbf{1}$	
	Buck1 OV	Yes	Yes	Yes	Yes	$\mathbf{1}$	
Fault 4	Buck1 HC	Yes	Yes	Yes	No	0.1	
Fault 5	NVM Read	No	Yes	No	No	\blacksquare	Ok/good when $bit = 1$
	PGOODCCBAT	Yes	Yes	Yes	No	0.1	
	VREFIN UVLO	Yes	Yes	Yes	Yes	1	Only monitored after Buck2 (VDDQ) rail soft-start is completed.
	AVDD UVPD	Yes	Yes	Yes	No	0.1	
Fault 6	NVM Error	No	Yes	Yes	No	$\overline{}$	
	CRST Triggered	Yes	Yes	Yes	No	\blacksquare	
	WDT Error	Yes	Yes	Yes	No	\blacksquare	
	OTP	Yes	Yes	Yes	No	\blacksquare	
	OTP Warn	Yes	Yes	Yes	No	$\overline{}$	
	EE Bank 7 ECC Corrected	No	Yes	No	No		Clear latched flag by writing 1 to the bit location
	EE Bank 6 ECC Corrected	No	Yes	No	No		Clear latched flag by writing 1 to the bit location
	EE Bank 5 ECC Corrected	No	Yes	No	No		Clear latched flag by writing 1 to the bit location
	EE Bank 4 ECC Corrected	No	Yes	No	No		Clear latched flag by writing 1 to the bit location
ECC Detail 1	EE Bank 3 ECC Corrected	No	Yes	No	No		Clear latched flag by writing 1 to the bit location
	EE Bank 2 ECC Corrected	No	Yes	No	No		Clear latched flag by writing 1 to the bit location
	EE Bank 1 ECC Corrected	No	Yes	No	No		Clear latched flag by writing 1 to the bit location
	EE Bank 0 ECC Corrected	No	Yes	No	No		Clear latched flag by writing 1 to the bit location

Table 10. Fault and Status Flags: Behavior and Partitioning (Cont.)

Fault Register Partitioning	Fault/Status Name	Live Bit Status	Latched Bit Status	INT# Mask Option	Fault Response Option	Deglitch Time (ms)	Notes
	EE Bank 7 ECC						
	Error	No	Yes	No	No		Clear latched flag by writing 1 to the bit location
	EE Bank 6 ECC Error	No	Yes	No	No		Clear latched flag by writing 1 to the bit location
ECC Detail 2	EE Bank 5 ECC Error	No	Yes	No	No		Clear latched flag by writing 1 to the bit location
	EE Bank 4 ECC Error	No	Yes	No	No		Clear latched flag by writing 1 to the bit location
	EE Bank 3ECC Error	No	Yes	No	No		Clear latched flag by writing 1 to the bit location
	EE Bank 2 ECC Error	No	Yes	No	No		Clear latched flag by writing 1 to the bit location
	EE Bank 1 ECC Error	No	Yes	No	No		Clear latched flag by writing 1 to the bit location
	EE Bank 0 ECC Error	No	Yes	No	No		Clear latched flag by writing 1 to the bit location
EE Detail	Valid EE Data	No	Yes	No	No		Clear latched flag by writing 1 to the bit location
	EE Error Latched	No	Yes	No	No		Clear latched flag by writing 1 to the bit location

Table 10. Fault and Status Flags: Behavior and Partitioning (Cont.)

9.16 Maximum Recommended Power Dissipation

The maximum power dissipation recommended in a package is calculated using [Equation 8](#page-68-0) where T_{JMAX} = Maximum junction temperature, T_{AMAX} = Maximum ambient temperature, $θ_{JA}$ = Thermal resistance of the package, and P_{DMAX} = Maximum power dissipation recommended.

(EQ. 8)

$$
\mathsf{P}_{\mathsf{DMAX}} = \frac{\mathsf{T}_{\mathsf{JMAX}} - \mathsf{T}_{\mathsf{AMAX}}}{\theta_{\mathsf{JA}}}
$$

An example of the maximum recommended power dissipation versus ambient temperature curve is shown in [Figure 37.](#page-69-0) In this example, the maximum power dissipation across the temperature range is specified at 25°C and the maximum junction temperature is set to 125°C, which is the maximum recommended operating junction temperature.

Figure 37. Power Dissipation vs Ambient Temperature

10. External Component Selection

The RAA215300 includes six synchronous buck regulators, three LDOs, and various features. It works with physically small components to reduce PCB assembly area and height. Switching MOSFETs are fully integrated and no external MOSFETs or diodes are required.

10.1 Output Filters

The inductor and output capacitors are low-pass filters for the voltage at the buck switching node. Their characteristics influence the transfer function of the regulator and the control loop. It the transient load changes, the capacitors maintain output voltage with greater effective bandwidth than that achievable by the control loop alone. The permissible values of inductance and capacitance are dictated by PMIC design and settings. The values in [Table 11](#page-70-0) are consistent with stable operation and performance in accordance with [Electrical](#page-10-0) [Specifications](#page-10-0).

10.1.1 Inductor Selection

At full load of the application, which is not necessarily the PMIC maximum rated load, inductors must have at least 90% of their low-current inductance. At 150% of PMIC maximum rated load, inductors must have at least 50% of their low-current inductance. For high efficiency, the inductors should have low resistance and low core loss. Choose molded or screened types for the best EMC.

Other similarly specified components may also be acceptable in the application, see [Recommended External](#page-70-1) [Components](#page-70-1).

10.1.2 Output Capacitor Selection

Capacitors must be ceramic. When selecting for capacitance value, account for the effects of operating voltage and temperature.

Ceramic capacitors have temperature and voltage (bias) coefficients, which can significantly derate their effective capacitance value. When choosing capacitors, the effective capacitance rating for a given package size, voltage rating, and applied temperature and DC bias must be considered to ensure enough capacitance is used in the design. X5R and X7R types are recommended, depending on operating temperature. Other similarly specified components may also be acceptable in the application, see [Recommended External Components.](#page-70-1)

10.2 Input Capacitor Selection

Ceramic input capacitors provide the high-frequency components of current flowing into the high-side MOSFETs. Place the capacitors close to the PMIC. If the power source is connected to the PMIC by long wires or traces, it may be necessary to add bulk capacitors near (not as close as the ceramic input capacitors) the PMIC to damp oscillation.

Other similarly specified components may also be acceptable in the application, see [Recommended External](#page-70-1) [Components](#page-70-1).

10.3 Recommended External Components

Table 11. Recommended External Components

Table 11. Recommended External Components (Cont.)

Table 11. Recommended External Components (Cont.)

1. The capacitance listed in the above table is not derated. Refer to the capacitors datasheets for effective capacitance.

2. Do Not Populate capacitors by default. They are only required for oscillator tuning. Renesas recommends placing footprints for these components in the system design in case they are required.

10.4 Recommended Effective Capacitance

The effective capacitance of the ceramic capacitors changes with the DC bias voltage. When choosing the input capacitors or output capacitors for each regulator, the total capacitance must be equivalent to the recommended value as shown in [Table 12](#page-72-1).

Table 12. Recommended Effective Capacitance[1]

1. The recommended effective capacitance is determined based on the [RTKA215300DE0000BU](https://www.renesas.com/RTKA215300DE0000BU) BOM and the DC characteristics curves that are available on the capacitor vendor website. The DC bias voltages are the typical input and output voltages of each regulator as stated in [Electrical Specifications.](#page-10-0)

11. Layout Guidelines

PCB design is crucial to proper performance of the PMIC and system. The following are recommendations to achieve proper device performance.

11.1 Power Ground (PGND)

PGND is the reference for all voltages of the power system. Many components must have low-impedance connections to PGND (most importantly the input and output capacitors). Create a PGND plane on at least one PCB layer and extend it to at least the connection points of all relevant components. The PGND plane is an important heatsink and it may also provide electrostatic screening. Aim to avoid interrupting the plane with non-PGND vias, especially if they are in a row and form a slit. The PGND plane is not perfect because it has impedance and there are unwanted voltages developed across it.

11.2 Analog Ground (AGND)

AGND is an electrically quiet reference for signals that could be corrupted if they were connected to PGND. These signals are the PMIC internal power supply and those associated with the RTC and its power supply. Create a small plane that connects these signals to Pin 26 and Pin 42. Connect this plane directly to PGND at the EPAD.

11.3 Digital Ground

Connect the grounds of digital signals to PGND.

11.4 Exposed Pad (EPAD)

Internal to the PMIC, all regulator power grounds are bonded to the EPAD. The EPAD is in close thermal contact with the PMIC die. Therefore, the connection between EPAD and PCB is important to both the grounding scheme and thermal management. Connect the EPAD to the PGND plane.

Place thermal vias, in a 1 to 1.2mm pitch grid formation, under the PMIC at least in the area of the EPAD, and connect them to the PGND plane. The vias must not wick solder from the EPAD joint.

11.5 Buck Regulators

The current through the MOSFETs is periodically and rapidly switched. The current generates a magnetic field that inductively couples current into nearby conductors. At some distance (dependent on frequency) from the

source, the magnetic field becomes electromagnetic radiation (noise). Voltage (noise) develops across impedance in the current paths.

To mitigate the effects of switched current, make paths short and low impedance, make loop areas small and avoid sharing ground connections with sensitive circuits.

The MOSFETs are internal to the PMIC, so their current paths are predetermined. The main external high-frequency current path is through input capacitors. Place input capacitors close to their respective buck regulator input terminals, which usually means placing them on the same side as the PMIC. Connect the positive side with short wide copper. If the negative side must connect to an inner-layer PGND plane, do so with multiple vias. In some applications, it might be helpful to place a physically small capacitor with a lower high-frequency impedance closest to the PMIC. Current in the inductor has smaller high-frequency content than the MOSFETs; however, it is still necessary to connect the inductor to the switch node PMIC terminals with low-impedance copper and to make low-impedance connections to the output capacitors. The output capacitors must be intimately connected to the PGND plane so use multiple vias if the PGND plane is on an inner layer.

The voltage at the switch node is periodically and rapidly switched. The voltage generates an electric field that capacitively couples voltage into nearby conductors. At some distance (dependent on frequency) from the source, the electric field becomes electromagnetic radiation (noise).

To mitigate the effects of switched voltage, make the copper area of the switched node small. This partially contradicts the requirement to make a low-impedance connection between the switch node and inductor, but this is a compromise that must happen. Make the path short but only wide enough to carry the current. Do not add copper that does not have a high current density. Most of the generated electric field is perpendicular to the copper surface. The PGND plane is an effective shield. The inductor terminal also generates an electric field, in directions perpendicular to its surfaces.

11.6 Linear Regulators (LDOs)

The LDOs require good high-frequency decoupling of their inputs and outputs. Connections to input and output capacitors must be low impedance at high frequency. Place capacitors close to PMIC pins and connect with short wide copper. Connect capacitors to the PGND plane with multiple vias.

11.7 Crystal Oscillator

Place the crystal close to the PMIC. Pin 28, XIN, has very high impedance, and oscillator circuits operating at low frequencies are susceptible to noise if good layout practice is not followed. Erratic clocking and accuracy errors can be caused by adjacent noisy signals. Do not route noisy traces near the crystal. Add a guard ring around the crystal and connect one end to AGND. To avoid affecting load capacitance, keep all layers clear of copper in the area of the crystal and its connecting traces.

11.8 Device Specific Layout Guidelines

The following table provides layout guidelines (such as trace routing and size, and component placements) for the various pins of RAA215300. *Note:* All buck supplies (BUCKx_VINx) = AVDD = VCHG.

12. Register Map

Any register addresses (pointers) not indicated in the following section, [Register Map Detail,](#page-77-0) are reserved and should not be used.

Register addresses 0x00 to 13 are read and write accessed using only the RTC Slave Address (set in register 0x1F).

All other register addresses are read and write accessed using the Main Slave Address (set in register 0x1E). See [7-bit Device Addresses.](#page-28-0)

12.1 Register Map Detail

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RAA215300 Datasheet

13. Package Outline Drawing

For the most recent package outline drawing, see [L56.8x8I](https://www.renesas.com/us/en/document/psc/l568x8i-56-lead-quad-flat-no-lead-plastic-package-5x5mm-exposed-paddle).

L56.8x8I

56 Lead Quad Flat No-lead Plastic Package (5x5mm Exposed Paddle) Rev 0, 11/20

1. Dimensions are in millimeters.

- Dimensions in () for reference only.
- Dimensioning and tolerancing conform to ASME Y14 5m-1994. $2.$
- $\overline{\mathbf{3}}$. Unless otherwise specified, tolerance: Decimal ±0.05
- Dimension applies to the metallized terminal and is measured \triangle between 0.15mm and 0.30mm from the terminal tip.
- $\hat{\mathbf{A}}$. Tiebar shown (if present) is a non-functional feature.
- $\hat{\mathbf{B}}$. The configuration of the pin #1 identifier is optional, but must be located within the zone indicated. The pin #1 identifier is either a mold or mark feature.

14. Ordering Information

1. These Pb-free plastic packaged products employ special Pb-free material sets, molding compounds/die attach materials, and 100% matte tin plate plus anneal (e3 termination finish, which is RoHS compliant and compatible with both SnPb and Pb-free soldering operations). Pb-free products are MSL classified at Pb-free peak reflow temperatures that meet or exceed the Pb-free requirements of IPC/JEDEC J-STD-020.

- 2. For Moisture Sensitivity Level (MSL), see the [RAA215300](https://www.renesas.com/RAA215300) product page. For more information about MSL, see [TB363](https://www.renesas.com/www/doc/tech-brief/tb363.pdf).
- 3. For a list of variants and key differences between them, see *[RAA215300 Datasheet Addendum](https://www.renesas.com/RAA215300#documents).*
- 4. For the Pb-Free Reflow Profile, see [TB493.](https://www.renesas.com/www/doc/tech-brief/tb493.pdf)
- 5. See [TB347](https://www.renesas.com/www/doc/tech-brief/tb347.pdf) for details about reel specifications.

15. Revision History

RAA215300 Datasheet

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